# 500 V / 600 V High Voltage 3-phase Motor Drivers
# SIM6800M/MV Series

**SanKen**

# Data Sheet

## Description

The SIM6800M/MV series are high voltage 3-phase motor drivers in which transistors, a pre-drive circuit, and bootstrap circuits (diodes and resistors) are highly integrated.

These products can run on a 3-shunt current detection system and optimally control the inverter systems of low- to medium-capacity motors that require universal input standards.

## Features

- Built-in Bootstrap Diodes with Current Limiting Resistors (60 Ω)
- CMOS-compatible Input (3.3 V or 5 V)
- Pb-free (RoHS Compliant)
- Isolation Voltage: 1500 V (for 1 min)
  UL-recognized Component (File No.: E118037)
  (SIM6880M UL Recognition Pending)
- Fault Signal Output at Protection Activation (FO Pin)
- High-side Shutdown Signal Input (SD Pin)
- Protections Include:
  Overcurrent Limit (OCL): Auto-restart
  Overcurrent Protection (OCP): Auto-restart
  Undervoltage Lockout for Power Supply
    High-side (UVLO_VB): Auto-restart
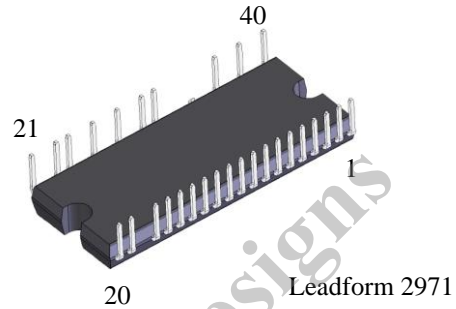    Low-side (UVLO_VCC): Auto-restart
  Thermal Shutdown (TSD): Auto-restart

## Typical Application
## (SIM6811M, SIM6812M)
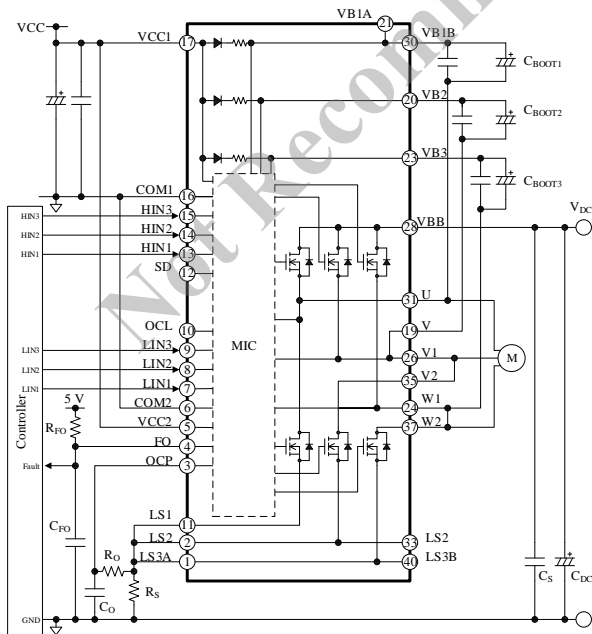


## Package

DIP40

Mold Dimensions: 36.0 mm × 14.8 mm × 4.0 mm



Leadform 2971

Not to scale

## Selection Guide

| $V_{DSS}/V_{CES}$ | $I_O$ | Part Number | Feature |
|---|---|---|---|
| 500 V | 2.0 A | SIM6811M | Power MOSFET |
| | 2.5 A | SIM6812M | |
| 600 V | 3.0 A | SIM6880M | IGBT with FRD, low switching dissipation |
| | 5.0 A | SIM6822MV | IGBT with FRD, low switching dissipation |

## Applications

For motor drives such as:

- Refrigerator Compressor Motor
- Fan Motor and Pump Motor for Washer and Dryer
- Fan Motor for Air Conditioner, Air Purifier, and Electric Fan

# Contents

## 1. Absolute Maximum Ratings

Current polarities are defined as follows: current going into the IC (sinking) is positive current (+); current coming out of the IC (sourcing) is negative current (−).

Unless specifically noted, $T_A = 25$ °C, COM1 = COM2 = COM.

| Parameter | Symbol | Conditions | Rating | Unit | Remarks |
|---|---|---|---|---|---|
| Main Supply Voltage (DC) [1] | $V_{DC}$ | VBB–LSx | 450 | V | SIM6822MV SIM6880M |
| Main Power Voltage (Surge) [1] | $V_{DC(SURGE)}$ | VBB–LSx | 500 | V | SIM6822MV SIM6880M |
| IGBT / Power MOSFET Breakdown Voltage | $V_{DSS}$ | $V_{CC} = 15$ V, $I_D = 1$ µA, $V_{IN} = 0$ V | 500 | V | SIM6811M SIM6812M |
| | $V_{CES}$ | $V_{CC} = 15$ V, $I_C = 1$ mA, $V_{IN} = 0$ V | 600 | | SIM6822MV SIM6880M |
| Logic Supply Voltage | $V_{CC}$ | VCCx–COM | 20 | V | |
| | $V_{BS}$ | VB1B–U, VB2–V, VB3–W1 | 20 | | |
| Output Current [2] | $I_O$ | $T_C = 25$ °C, $T_J < 150$ °C | 2 | A | SIM6811M |
| | | | 2.5 | | SIM6812M |
| | | | 3 | | SIM6880M |
| | | | 5 | | SIM6822MV |
| Output Current (Pulse) | $I_{OP}$ | $T_C = 25$ °C, $V_{CC} = 15$ V, pulse width ≤ 1 ms, single pulse | 3 | A | SIM6811M |
| | | | 3.75 | | SIM6812M |
| | | | 4.5 | | SIM6880M |
| | | | 7.5 | | SIM6822MV |
| Input Voltage | $V_{IN}$ | HINx–COM, LINx–COM | − 0.5 to 7 | V | |
| FO Pin Voltage | $V_{FO}$ | FO–COM | −0.5 to 7 | V | |
| OCP Pin Voltage | $V_{OCP}$ | OCP–COM | −0.5 to 7 | V | |
| SD Pin Voltage | $V_{SD}$ | SD–COM | −0.5 to 7 | V | |
| LSx Pin Voltage (DC) | $V_{LS(DC)}$ | LSx–COM | −0.5 to 7 | V | |
| LSx Pin Voltage (Surge) | $V_{LS(SURGE)}$ | LSx–COM | −4 to 7 | V | |
| Operating Case Temperature [3] | $T_{C(OP)}$ | | −30 to 100 | °C | |
| Junction Temperature [4] | $T_J$ | | 150 | °C | |
| Storage Temperature | $T_{STG}$ | | −40 to 150 | °C | |
| Isolation Voltage [5] | $V_{ISO(RMS)}$ | Between surface of the case and each pin; AC, 60 Hz, 1 min | 1500 | V | |

---

[1] Defined for the IGBT-embedded device only.

[2] Should be derated depending on an actual case temperature. See Section 15.4.

[3] Refers to a case temperature measured during IC operation.

[4] Refers to the junction temperature of each chip built in the IC, including the control MIC, transistors, and freewheeling diodes.

[5] Refers to voltage conditions to be applied between all of the pins and the case. All the pins have to be shorted.

## 2. Recommended Operating Conditions

Unless specifically noted, COM1 = COM2 = COM.

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit | Remarks |
|---|---|---|---|---|---|---|---|
| Main Supply Voltage | $V_{DC}$ | VBB–COM | — | 300 | 400 | V | |
| Logic Supply Voltage | $V_{CC}$ | VCCx–COM | 13.5 | 15.0 | 16.5 | V | |
| | $V_{BS}$ | VB1B–U, VB2–V, VB3–W1 | 13.5 | — | 16.5 | V | |
| Input Voltage (HINx, LINx, OCP, SD, FO) | $V_{IN}$ | | 0 | — | 5.5 | V | |
| Minimum Input Pulse Width | $t_{IN(MIN)ON}$ | | 0.5 | — | — | μs | |
| | $t_{IN(MIN)OFF}$ | | 0.5 | — | — | μs | |
| Dead Time of Input Signal | $t_{DEAD}$ | | 1.5 | — | — | μs | |
| FO Pin Pull-up Resistor | $R_{FO}$ | | 3.3 | — | 10 | kΩ | |
| FO Pin Pull-up Voltage | $V_{FO}$ | | 3.0 | — | 5.5 | V | |
| FO Pin Noise Filter Capacitor | $C_{FO}$ | | 0.001 | — | 0.01 | μF | |
| Bootstrap Capacitor | $C_{BOOT}$ | | 1 | — | 220 | μF | |
| Shunt Resistor* | $R_S$ | $I_{OP} \leq 3$ A | 390 | — | — | mΩ | SIM6811M |
| | | $I_{OP} \leq 3.75$ A | 270 | — | — | | SIM6812M |
| | | $I_{OP} \leq 4.5$ A | 270 | — | — | | SIM6880M |
| | | $I_{OP} \leq 7.5$ A | 150 | — | — | | SIM6822MV |
| RC Filter Resistor | $R_O$ | | — | — | 100 | Ω | |
| RC Filter Capacitor | $C_O$ | | 1000 | — | 2200 | pF | SIM6822MV SIM6880M |
| | | | 1000 | — | 10000 | | SIM6811M SIM6812M |
| PWM Carrier Frequency | $f_C$ | | — | — | 20 | kHz | |
| Operating Case Temperature | $T_{C(OP)}$ | | — | — | 100 | °C | |

---

\* Should be a low-inductance resistor.

## 3. Electrical Characteristics

Current polarities are defined as follows: current going into the IC (sinking) is positive current (+); current coming out of the IC (sourcing) is negative current (−).

Unless specifically noted, $T_A$ = 25 °C, $V_{CC}$ = 15 V, COM1 = COM2 = COM.

### 3.1 Characteristics of Control Parts

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit | Remarks |
|---|---|---|---|---|---|---|---|
| **Power Supply Operation** | | | | | | | |
| Logic Operation Start Voltage | $V_{CC(ON)}$ | VCCx–COM | 10.5 | 11.5 | 12.5 | V | |
| | $V_{BS(ON)}$ | VB1B–U, VB2–V, VB3–W1 | 9.5 | 10.5 | 11.5 | V | |
| Logic Operation Stop Voltage | $V_{CC(OFF)}$ | VCCx–COM | 10.0 | 11.0 | 12.0 | V | |
| | $V_{BS(OFF)}$ | VB1B–U, VB2–V, VB3–W1 | 9.0 | 10.0 | 11.0 | V | |
| Logic Supply Current | $I_{CC}$ | VCC1 = VCC2, VCC pin current in 3-phase operation | — | 3.2 | 4.5 | mA | |
| | $I_{BS}$ | VB1B–U or VB2–V or VB3–W1; HINx = 5 V; VBx pin current in 1-phase operation | — | 140 | 400 | μA | |
| **Input Signal** | | | | | | | |
| High Level Input Threshold Voltage (HINx, LINx, SD, FO) | $V_{IH}$ | | — | 2.0 | 2.5 | V | |
| Low Level Input Threshold Voltage (HINx, LINx, SD, FO) | $V_{IL}$ | | 1.0 | 1.5 | — | V | |
| High Level Input Current (HINx, LINx) | $I_{IH}$ | $V_{IN}$ = 5 V | — | 230 | 500 | μA | |
| Low Level Input Current (HINx, LINx) | $I_{IL}$ | $V_{IN}$ = 0 V | — | — | 2 | μA | |
| **Fault Signal Output** | | | | | | | |
| FO Pin Voltage at Fault Signal Output | $V_{FOL}$ | $V_{FO}$ = 5 V, $R_{FO}$ = 10 kΩ | 0 | — | 0.5 | V | |
| FO Pin Voltage in Normal Operation | $V_{FOH}$ | $V_{FO}$ = 5 V, $R_{FO}$ = 10 kΩ | 4.8 | — | — | V | |
| **Protection** | | | | | | | |
| OCL Pin Output Voltage (L) | $V_{OCL(L)}$ | | 0 | — | 0.5 | V | |
| OCL Pin Output Voltage (H) | $V_{OCL(H)}$ | | 4.5 | — | 5.5 | V | |
| Current Limit Reference Voltage | $V_{LIM}$ | | 0.6175 | 0.6500 | 0.6825 | V | |
| OCP Threshold Voltage | $V_{TRIP}$ | | 0.9 | 1.0 | 1.1 | V | |
| OCP Hold Time | $t_P$ | | 20 | 25 | — | μs | |
| OCP Blanking Time | $t_{BK(OCP)}$ | | — | 2 | — | μs | |
| Current Limit Blanking Time | $t_{BK(OCL)}$ | | — | 2 | — | μs | |
| TSD Operating Temperature | $T_{DH}$ | | 135 | 150 | 165 | °C | |
| TSD Releasing Temperature | $T_{DL}$ | | 105 | 120 | 135 | °C | |

## 3.2 Bootstrap Diode Characteristics

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit | Remarks |
|---|---|---|---|---|---|---|---|
| Bootstrap Diode Leakage Current | $I_{LBD}$ | $V_R = 500$ V | — | — | 10 | μA | |
| Bootstrap Diode Forward Voltage | $V_{FB}$ | $I_{FB} = 0.15$ A | — | 1.0 | 1.3 | V | |
| Bootstrap Diode Series Resistor | $R_{BOOT}$ | | 45 | 60 | 75 | Ω | |

## 3.3 Thermal Resistance Characteristics

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit | Remarks |
|---|---|---|---|---|---|---|---|
| Junction-to-Case Thermal Resistance[1] | $R_{J-C}$ | All power MOSFETs operating | — | — | 3.6 | °C/W | SIM6811M SIM6812M |
| | $R_{(J-C)Q}$[2] | All IGBTs operating | — | — | 3.6 | °C/W | SIM6822MV SIM6880M |
| | $R_{(J-C)F}$[3] | All freewheeling diodes operating | — | — | 4.2 | °C/W | SIM6822MV SIM6880M |
| Junction-to-Ambient Thermal Resistance | $R_{J-A}$ | All power MOSFETs operating | — | — | 25 | °C/W | SIM6811M SIM6812M |
| | $R_{(J-A)Q}$ | All IGBTs operating | — | — | 25 | °C/W | SIM6822MV SIM6880M |
| | $R_{(J-A)F}$ | All freewheeling diodes operating | — | — | 29 | °C/W | SIM6822MV SIM6880M |
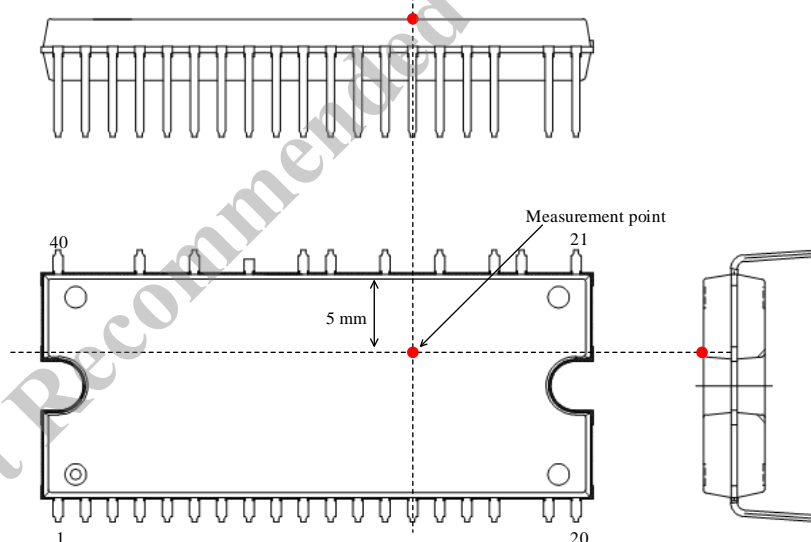


Figure 3-1.   Case Temperature Measurement Point

---

[1] Refers to a case temperature at the measurement point described in Figure 3-1, below.

[2] Refers to steady-state thermal resistance between the junction of the built-in transistors and the case. For transient thermal characteristics, see Section 15.1.

[3] Refers to steady-state thermal resistance between the junction of the built-in freewheeling diodes and the case.

## 3.4 Transistor Characteristics

Figure 3-2 provides the definitions of switching characteristics described in this and the following sections.
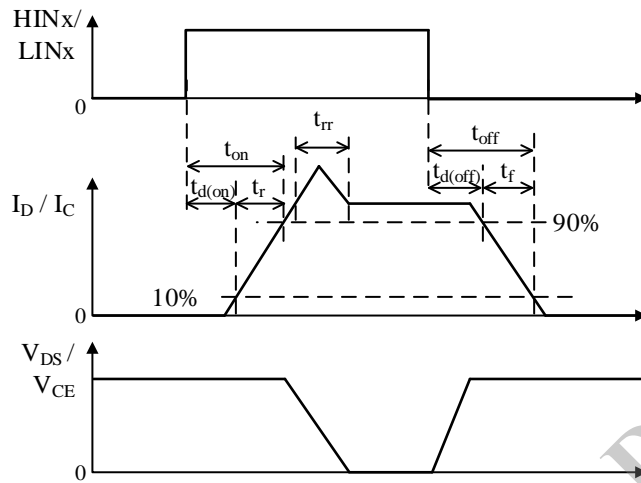


Figure 3-2. Switching Characteristics Definitions

### 3.4.1 SIM6811M

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| Drain-to-Source Leakage Current | $I_{DSS}$ | $V_{DS}$ = 500 V, $V_{IN}$ = 0 V | — | — | 100 | μA |
| Drain-to-Source On-resistance | $R_{DS(ON)}$ | $I_D$ = 1.0 A, $V_{IN}$ = 5 V | — | 3.2 | 4.0 | Ω |
| Source-to-Drain Diode Forward Voltage | $V_{SD}$ | $I_{SD}$ =1.0 A, $V_{IN}$ = 0 V | — | 1.0 | 1.5 | V |
| **High-side Switching** | | | | | | |
| Source-to-Drain Diode Reverse Recovery Time | $t_{rr}$ | $V_{DC}$ = 300 V, $I_D$ = 2.0 A, inductive load, $V_{IN}$ = 0→5 V or 5→0 V, $T_J$ = 25 °C | — | 150 | — | ns |
| Turn-on Delay Time | $t_{d(on)}$ | | — | 770 | — | ns |
| Rise Time | $t_r$ | | — | 70 | — | ns |
| Turn-off Delay Time | $t_{d(off)}$ | | — | 690 | — | ns |
| Fall Time | $t_f$ | | — | 30 | — | ns |
| **Low-side Switching** | | | | | | |
| Source-to-Drain Diode Reverse Recovery Time | $t_{rr}$ | $V_{DC}$ = 300 V, $I_D$ = 2.0 A, inductive load, $V_{IN}$ = 0→5 V or 5→0 V, $T_J$ = 25 °C | — | 150 | — | ns |
| Turn-on Delay Time | $t_{d(on)}$ | | — | 690 | — | ns |
| Rise Time | $t_r$ | | — | 90 | — | ns |
| Turn-off Delay Time | $t_{d(off)}$ | | — | 650 | — | ns |
| Fall Time | $t_f$ | | — | 50 | — | ns |

### 3.4.2   SIM6812M

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| Drain-to-Source Leakage Current | $I_{CES}$ | $V_{DS}$ = 500 V, $V_{IN}$ = 0 V | — | — | 100 | μA |
| Drain-to-Source On-resistance | $V_{CE(SAT)}$ | $I_D$ = 1.25 A, $V_{IN}$ = 5 V | — | 2.0 | 2.4 | Ω |
| Source-to-Drain Diode Forward Voltage | $V_F$ | $I_{SD}$ =1.25 A, $V_{IN}$ = 0 V | — | 1.0 | 1.5 | V |
| **High-side Switching** | | | | | | |
| Source-to-Drain Diode Reverse Recovery Time | $t_{rr}$ | $V_{DC}$ = 300 V, $I_D$ = 2.5 A, inductive load, $V_{IN}$ = 0→5 V or 5→0 V, $T_J$ = 25 °C | — | 140 | — | ns |
| Turn-on Delay Time | $t_{d(on)}$ | | — | 910 | — | ns |
| Rise Time | $t_r$ | | — | 100 | — | ns |
| Turn-off Delay Time | $t_{d(off)}$ | | — | 700 | — | ns |
| Fall Time | $t_f$ | | — | 40 | — | ns |
| **Low-side Switching** | | | | | | |
| Source-to-Drain Diode Reverse Recovery Time | $t_{rr}$ | $V_{DC}$ = 300 V, $I_D$ = 2.5 A, inductive load, $V_{IN}$ = 0→5 V or 5→0 V, $T_J$ = 25 °C | — | 155 | — | ns |
| Turn-on Delay Time | $t_{d(on)}$ | | — | 875 | — | ns |
| Rise Time | $t_r$ | | — | 110 | — | ns |
| Turn-off Delay Time | $t_{d(off)}$ | | — | 775 | — | ns |
| Fall Time | $t_f$ | | — | 35 | — | ns |

### 3.4.3   SIM6880M

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| Collector-to-Emitter Leakage Current | $I_{CES}$ | $V_{CE}$ = 600 V, $V_{IN}$ = 0 V | — | — | 1 | mA |
| Collector-to-Emitter Saturation Voltage | $V_{CE(SAT)}$ | $I_C$ = 3.0 A, $V_{IN}$ = 5 V | — | 1.85 | 2.30 | V |
| Diode Forward Voltage | $V_F$ | $I_F$ = 3.0 A, $V_{IN}$ = 0 V | — | 2.0 | 2.4 | V |
| **High-side Switching** | | | | | | |
| Diode Reverse Recovery Time | $t_{rr}$ | $V_{DC}$ = 300 V, $I_C$ = 3.0 A, inductive load, $V_{IN}$ = 0→5 V or 5→0 V, $T_J$ = 25 °C | — | 100 | — | ns |
| Turn-on Delay Time | $t_{d(on)}$ | | — | 880 | — | ns |
| Rise Time | $t_r$ | | — | 120 | — | ns |
| Turn-off Delay Time | $t_{d(off)}$ | | — | 740 | — | ns |
| Fall Time | $t_f$ | | — | 210 | — | ns |
| **Low-side Switching** | | | | | | |
| Diode Reverse Recovery Time | $t_{rr}$ | $V_{DC}$ = 300 V, $I_C$ = 3.0 A, inductive load, $V_{IN}$ = 0→5 V or 5→0 V, $T_J$ = 25 °C | — | 100 | — | ns |
| Turn-on Delay Time | $t_{d(on)}$ | | — | 820 | — | ns |
| Rise Time | $t_r$ | | — | 140 | — | ns |
| Turn-off Delay Time | $t_{d(off)}$ | | — | 660 | — | ns |
| Fall Time | $t_f$ | | — | 200 | — | ns |

### 3.4.4    SIM6822MV

| Parameter | Symbol | Conditions | Min. | Typ. | Max. | Unit |
|---|---|---|---|---|---|---|
| Collector-to-Emitter Leakage Current | $I_{CES}$ | $V_{CE} = 600$ V, $V_{IN} = 0$ V | — | — | 1 | mA |
| Collector-to-Emitter Saturation Voltage | $V_{CE(SAT)}$ | $I_C = 5$ A, $V_{IN} = 5$ V | — | 1.75 | 2.2 | V |
| Diode Forward Voltage | $V_F$ | $I_F = 5$ A, $V_{IN} = 0$ V | — | 2.0 | 2.4 | V |
| **High-side Switching** | | | | | | |
| Diode Reverse Recovery Time | $t_{rr}$ | $V_{DC} = 300$ V, $I_C = 5$ A, inductive load, $V_{IN} = 0{\rightarrow}5$ V or $5{\rightarrow}0$ V, $T_J = 25$ °C | — | 80 | — | ns |
| Turn-on Delay Time | $t_{d(on)}$ | | — | 740 | — | ns |
| Rise Time | $t_r$ | | — | 70 | — | ns |
| Turn-off Delay Time | $t_{d(off)}$ | | — | 570 | — | ns |
| Fall Time | $t_f$ | | — | 100 | — | ns |
| **Low-side Switching** | | | | | | |
| Diode Reverse Recovery Time | $t_{rr}$ | $V_{DC} = 300$ V, $I_C = 5$ A, inductive load, $V_{IN} = 0{\rightarrow}5$ V or $5{\rightarrow}0$ V, $T_J = 25$ °C | — | 80 | — | ns |
| Turn-on Delay Time | $t_{d(on)}$ | | — | 690 | — | ns |
| Rise Time | $t_r$ | | — | 100 | — | ns |
| Turn-off Delay Time | $t_{d(off)}$ | | — | 540 | — | ns |
| Fall Time | $t_f$ | | — | 100 | — | ns |

## 4.  Mechanical Characteristics

| Parameter | Conditions | Min. | Typ. | Max. | Unit | Remarks |
|---|---|---|---|---|---|---|
| Heatsink Mounting Screw Torque | * | 0.294 | — | 0.441 | N·m | |
| Flatness of Heatsink Attachment Area | See Figure 4-1. | 0 | — | 100 | μm | |
| Package Weight | | — | 5.2 | — | g | |

* Requires using a metric screw of M2.5 and a plain washer of 6.0 mm (φ). For more on screw tightening, see Section 13.2.
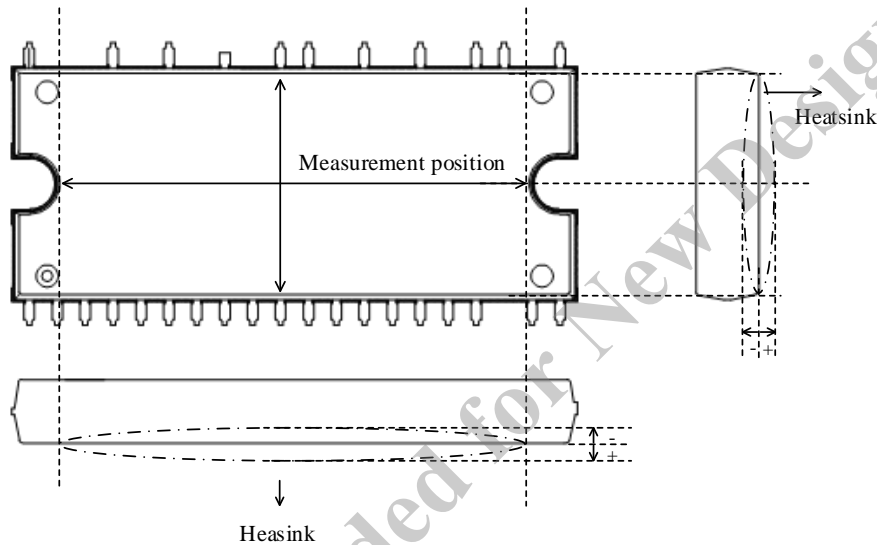


Figure 4-1.   Flatness Measurement Position

## 5.  Insulation Distance

| Parameter | Conditions | Min. | Typ. | Max. | Unit | Remarks |
|---|---|---|---|---|---|---|
| Clearance | Between heatsink* and leads. See Figure 5-1. | 1.5 | — | 2.1 | mm | |
| Creepage | | 1.7 | — | — | mm | |

* Refers to when a heatsink to be mounted is flat. If your application requires a clearance exceeding the maximum distance given above, use an alternative (e.g., a convex heatsink) that will meet the target requirement.
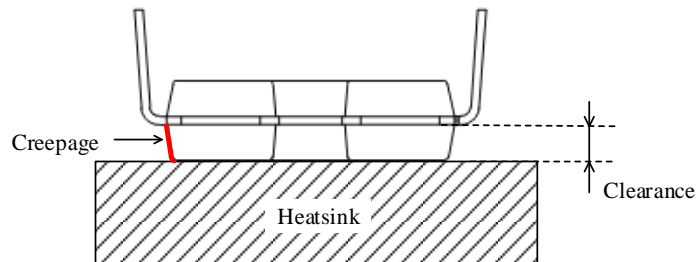


Figure 5-1.   Insulation Distance Definitions

## 6. Truth Table

Table 6-1 is a truth table that provides the logic level definitions of operation modes.

In the case where HINx and LINx pin signals in each phase are high at the same time, both the high- and low-side transistors become on (simultaneous on-state). Therefore, HINx and LINx signals, the input signals for the HINx and LINx pins, require dead time setting so that such a simultaneous on-state event can be avoided.

After the IC recovers from a UVLO_VCC condition, the low-side transistors resume switching in accordance with the input logic levels of the LINx signals (level-triggered), whereas the high-side transistors resume switching at the next rising edge of an HINx signal (edge-triggered).

After the IC recovers from a UVLO_VB condition, the high-side transistors resume switching at the next rising edge of an HINx signal (edge-triggered).

Table 6-1.   Truth Table for Operation Modes

| Mode | HINx | LINx | High-side Transistor | Low-side Transistor |
|---|---|---|---|---|
| Normal Operation | L | L | OFF | OFF |
| | H | L | ON | OFF |
| | L | H | OFF | ON |
| | H | H | ON | ON |
| External Shutdown Signal Input FO = Low Level | L | L | OFF | OFF |
| | H | L | ON | OFF |
| | L | H | OFF | OFF |
| | H | H | ON | OFF |
| Undervoltage Lockout for High-side Power Supply (UVLO_VB) | L | L | OFF | OFF |
| | H | L | OFF | OFF |
| | L | H | OFF | ON |
| | H | H | OFF | ON |
| Undervoltage Lockout for Low-side Power Supply (UVLO_VCC) | L | L | OFF | OFF |
| | H | L | OFF | OFF |
| | L | H | OFF | OFF |
| | H | H | OFF | OFF |
| Overcurrent Protection (OCP) | L | L | OFF | OFF |
| | H | L | ON | OFF |
| | L | H | OFF | OFF |
| | H | H | ON | OFF |
| Overcurrent Limit (OCL) (OCL = SD) | L | L | OFF | OFF |
| | H | L | OFF | OFF |
| | L | H | OFF | ON |
| | H | H | OFF | ON |
| Thermal Shutdown (TSD) | L | L | OFF | OFF |
| | H | L | ON | OFF |
| | L | H | OFF | OFF |
| | H | H | ON | OFF |

# 7. Block Diagrams
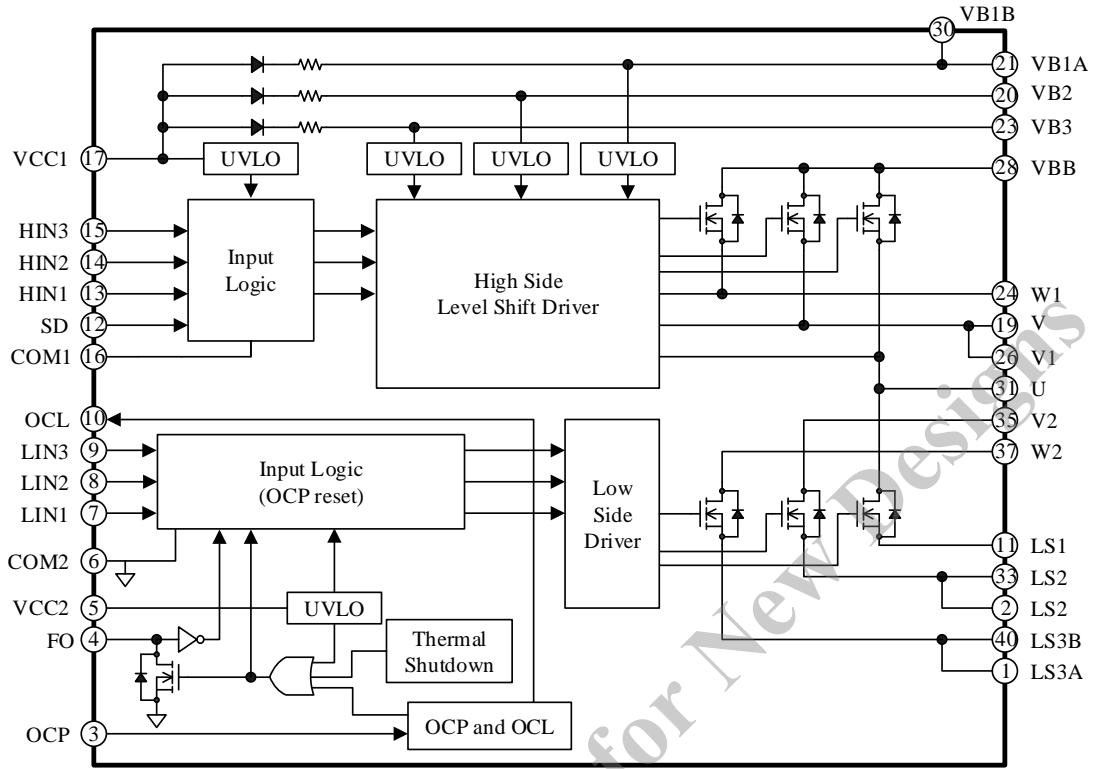


Figure 7-1.    SIM6811M or SIM6812M
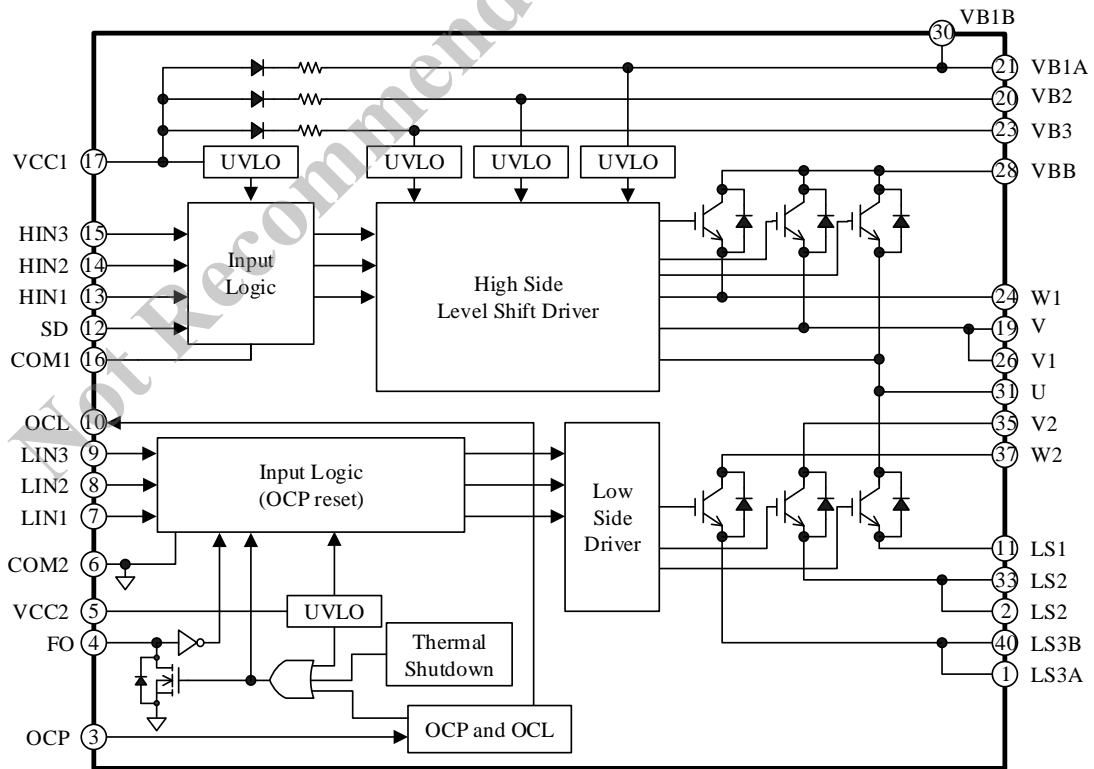


Figure 7-2.    SIM6822MV or SIM6880M

## 8.    Pin Configuration Definitions

Top View
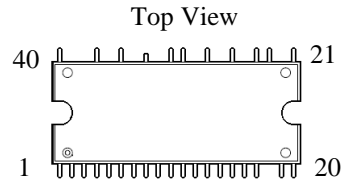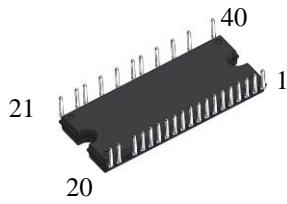
| Pin Number | Pin Name | Description |
|---|---|---|
| 1 | LS3A | W-phase IGBT emitter, or power MOSFET source |
| 2 | LS2 | V-phase IGBT emitter, or power MOSFET source |
| 3 | OCP | Overcurrent protection signal input |
| 4 | FO | Fault signal output and shutdown signal input |
| 5 | VCC2 | Low-side logic supply voltage input |
| 6 | COM2 | Low-side logic ground |
| 7 | LIN1 | Logic input for U-phase low-side gate driver |
| 8 | LIN2 | Logic input for V-phase low-side gate driver |
| 9 | LIN3 | Logic input for W-phase low-side gate driver |
| 10 | OCL | Overcurrent limit signal output |
| 11 | LS1 | U-phase IGBT emitter, or power MOSFET source |
| 12 | SD | High-side shutdown signal input |
| 13 | HIN1 | Logic input for U-phase high-side gate driver |
| 14 | HIN2 | Logic input for V-phase high-side gate driver |
| 15 | HIN3 | Logic input for W-phase high-side gate driver |
| 16 | COM1 | High-side logic ground |
| 17 | VCC1 | High-side logic supply voltage input |
| 18 | — | (Pin removed) |
| 19 | V | Bootstrap capacitor connection for V-phase |
| 20 | VB2 | V-phase high-side floating supply voltage input |
| 21 | VB1A | U-phase high-side floating supply voltage input |
| 22 | — | (Pin removed) |
| 23 | VB3 | W-phase high-side floating supply voltage input |
| 24 | W1 | W-phase output (connected to W2 externally) |
| 25 | — | (Pin removed) |
| 26 | V1 | V-phase output (connected to V2 externally) |
| 27 | — | (Pin removed) |
| 28 | VBB | Positive DC bus supply voltage |
| 29 | — | (Pin removed) |
| 30 | VB1B | U-phase high-side floating supply voltage input |
| 31 | U | U-phase output |
| 32 | — | (Pin removed) |
| 33 | LS2 | (Pin trimmed) V-phase IGBT emitter, or power MOSFET source |
| 34 | — | (Pin removed) |
| 35 | V2 | V-phase output (connected to V1 externally) |
| 36 | — | (Pin removed) |
| 37 | W2 | W-phase output (connected to W1 externally) |
| 38 | — | (Pin removed) |
| 39 | — | (Pin removed) |
| 40 | LS3B | W-phase IGBT emitter, or power MOSFET source |

## 9. Typical Applications

CR filters and Zener diodes should be added to your application as needed. This is to protect each pin against surge voltages causing malfunctions, and to avoid the IC being used under the conditions exceeding the absolute maximum ratings where critical damage is inevitable. Then, check all the pins thoroughly under actual operating conditions to ensure that your application works flawlessly.
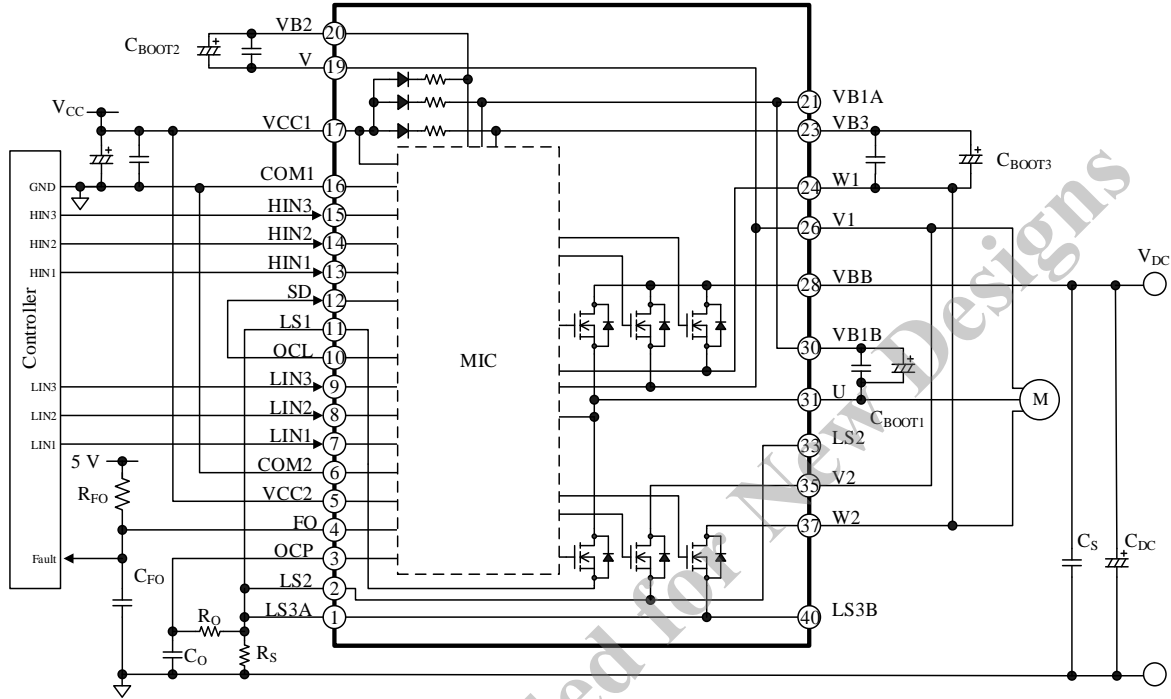


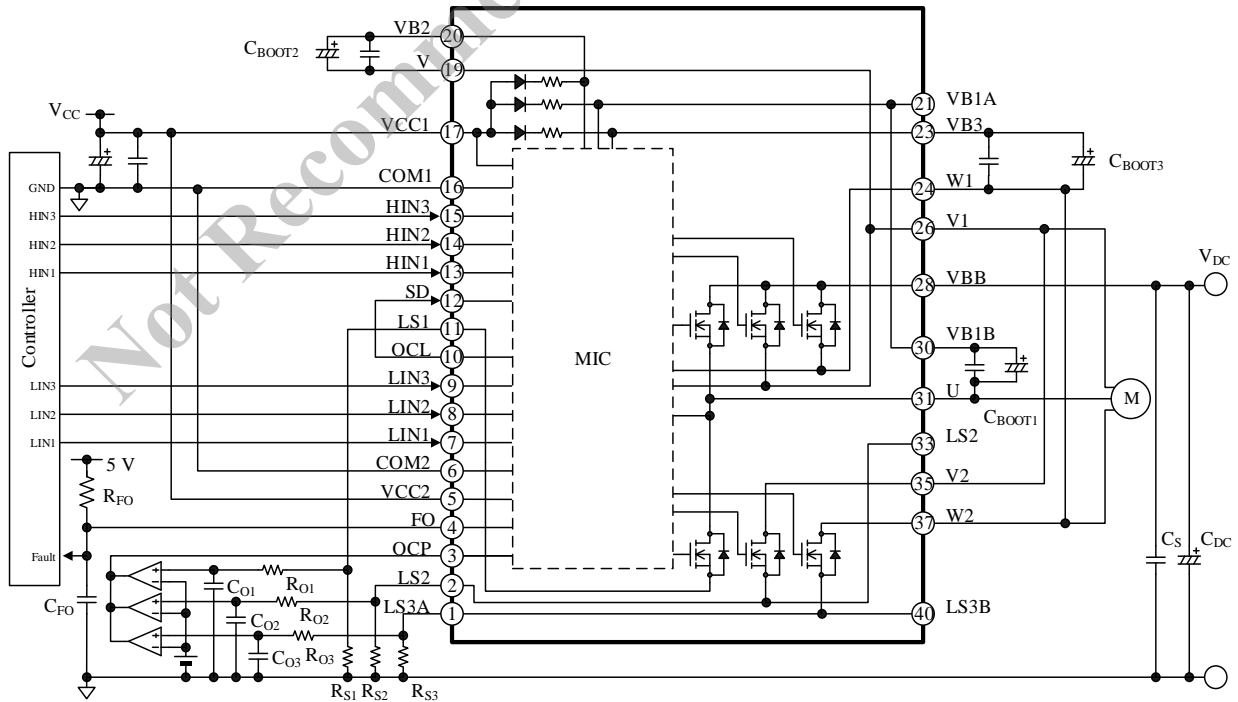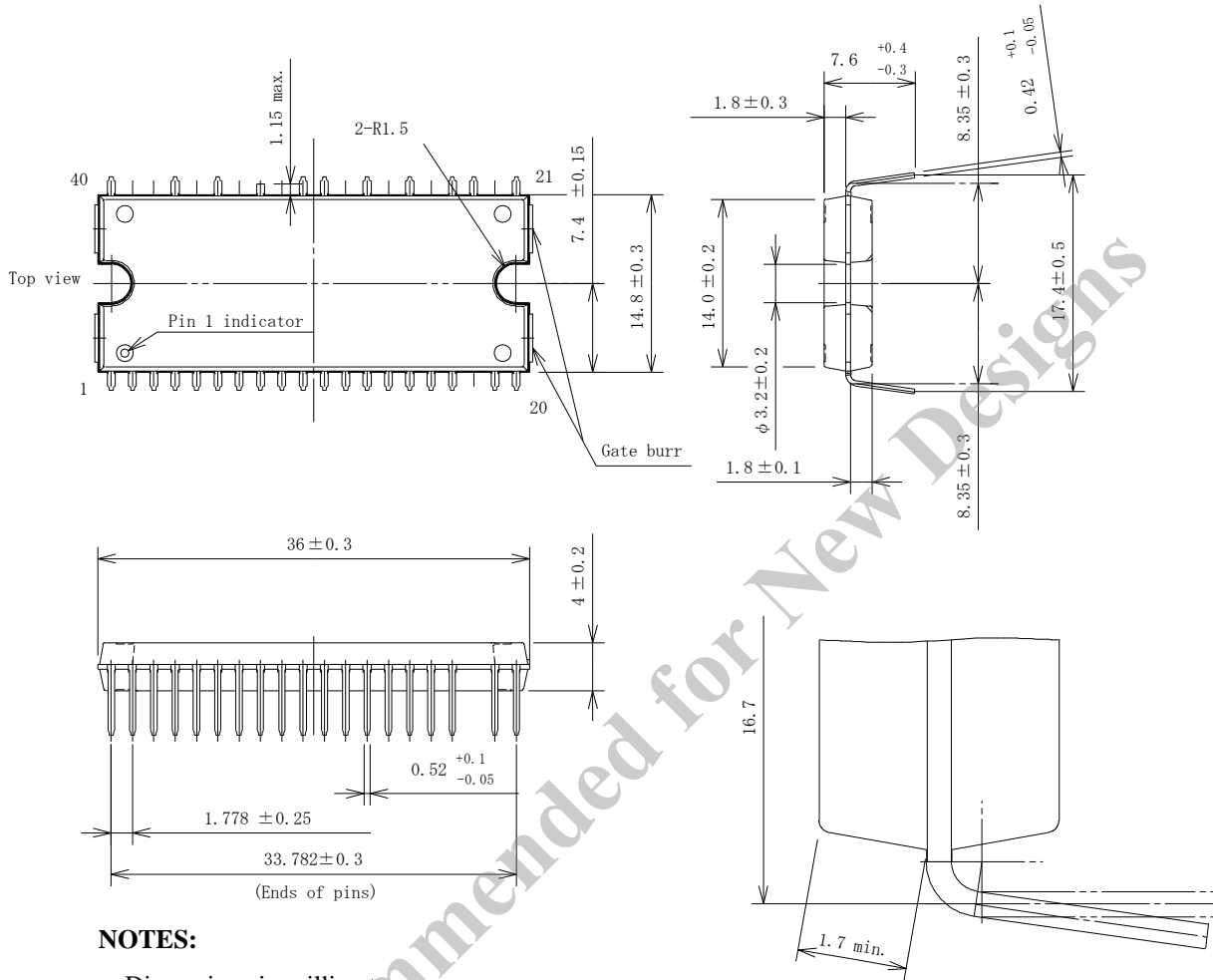Figure 9-1. SIM6811M / SIM6812M Typical Application Using a Single Shunt Resistor



Figure 9-2. SIM6811M / SIM6812M Typical Application Using Three Shunt Resistors

## 10.  Physical Dimensions

● **DIP40 Package**



**NOTES:**

- Dimensions in millimeters
- Pb-free (RoHS compliant)
- The leads illustrated above are for reference only, and may not be actual states of being bent.
- Maximum gate burr height is 0.3 mm.

● **Reference Through Hole Size and Layout**



Unit: mm
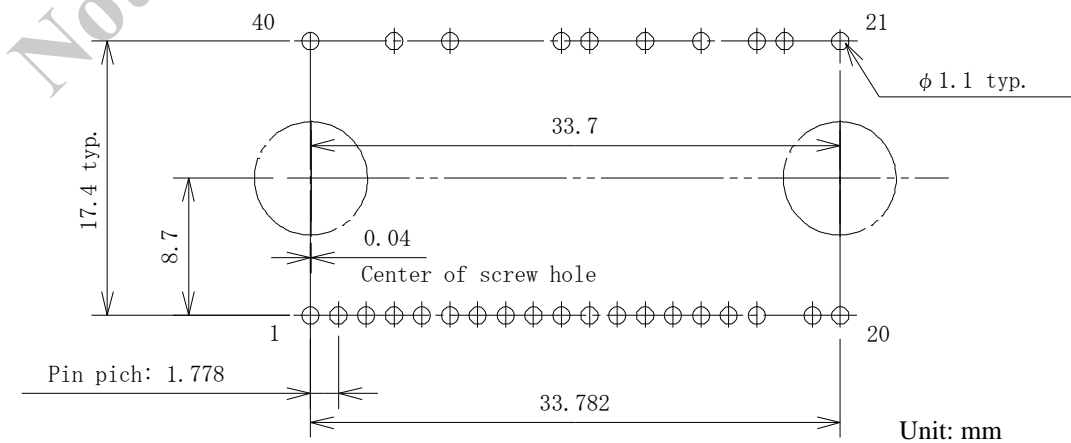
## 11. Marking Diagram

● **SIM6800M Series**

```
40                                      21
    SIM68xxM  --------------- Part Number
                           Lot Number:
    SK  YMDD X                Y is the last digit of the year of manufacture (0 to 9)
                              M is the month of the year (1 to 9, O, N, or D)
                              DD is the day of the month (01 to 31)
1                              20
                        ------- Control Number
                              X is the control symbol (A to Z)
```

● **SIM6800MV Series**

```
40                                      21
    SIM68xxM  --------------- Part Number
                           Lot Number:
    SK  YMDD XV               Y is the last digit of the year of manufacture (0 to 9)
                              M is the month of the year (1 to 9, O, N, or D)
                              DD is the day of the month (01 to 31)
1                              20
                        ------- Control Number
                              X is the control symbol (A to Z)
                              V is the control symbol
```

## 12. Functional Descriptions

Unless specifically noted, this section uses the following definitions:

- All the characteristic values given in this section are typical values.
- All the circuit diagrams listed in this section represent the type of IC that incorporates power MOSFETs. All the functional descriptions in this section are also applicable to the type of IC that incorporates IGBTs.
- For pin and peripheral component descriptions, this section employs a notation system that denotes a pin name with the arbitrary letter "x", depending on context. Thus, "the VCCx pin" is used when referring to either or both of the VCC1 and VCC2 pins.
- The COM1 pin is always connected to the COM2 pin.

### 12.1 Turning On and Off the IC

The procedures listed below provide recommended startup and shutdown sequences. To turn on the IC properly, do not apply any voltage on the VBB, HINx, and LINx pins until the VCCx pin voltage has reached a stable state ($V_{CC(ON)} \geq 12.5$ V).

It is required to fully charge bootstrap capacitors, $C_{BOOTx}$, at startup (see Section 12.2.2).

To turn off the IC, set the HINx and LINx pins to logic low (or "L"), and then decrease the VCCx pin voltage.

### 12.2 Pin Descriptions

#### 12.2.1 U, V, V1, V2, W1, and W2

The U, V1, V2, W1, and W2 pins are the outputs of the three phases, and serve as the connection terminals to the 3-phase motor. The V pin must be connected to a bootstrap capacitor of the V-phase. Do not connect the 3-phase motor to the V pin. The V1 and W1 pins must be connected to the V2 and W2 pins on a PCB, respectively.

The U, V (V1) and W1 pins are the grounds for the VB1A (VB1B), VB2, and VB3 pins.

The U, V and W1 pins are connected to the negative nodes of bootstrap capacitors, $C_{BOOTx}$. The V pin is internally connected to the V1 pin.

Since high voltages are applied to these output pins (U, V1, V2, W1, and W2), it is required to take measures for insulating as follows:

- Keep enough distance between the output pins and low-voltage traces.
- Coat the output pins with insulating resin.

#### 12.2.2 VB1A, VB1B, VB2, and VB3

These pins are connected to bootstrap capacitors for the high-side floating supply.

In actual applications, use either of the VB1A or VB1B pin because they are internally connected. Voltages across the VBx and these output pins should be maintained within the recommended range (i.e., the Logic Supply Voltage, $V_{BS}$) given in Section 2.

A bootstrap capacitor, $C_{BOOTx}$, should be connected in each of the traces between the VB1A (VB1B) and U pins, the VB2 and V pins, the VB3 and W1 pins.

For proper startup, turn on the low-side transistor first, then fully charge the bootstrap capacitor, $C_{BOOTx}$.

For the capacitance of the bootstrap capacitors, $C_{BOOTx}$, choose the values that satisfy Equations (1) and (2). Note that capacitance tolerance and DC bias characteristics must be taken into account when you choose appropriate values for $C_{BOOTx}$.

$$C_{BOOTx} (\mu F) > 800 \times t_{L(OFF)} \tag{1}$$

$$1\ \mu F \leq C_{BOOTx} \leq 220\ \mu F \tag{2}$$

In Equation (1), let $t_{L(OFF)}$ be the maximum off-time of the low-side transistor (i.e., the non-charging time of $C_{BOOTx}$), measured in seconds.

Even while the high-side transistor is off, voltage across the bootstrap capacitor keeps decreasing due to power dissipation in the IC. When the VBx pin voltage decreases to $V_{BS(OFF)}$ or less, the high-side undervoltage lockout (UVLO_VB) starts operating (see Section 12.3.3.1). Therefore, actual board checking should be done thoroughly to validate that voltage across the VBx pin maintains over 11.0 V ($V_{BS} > V_{BS(OFF)}$) during a low-frequency operation such as a startup period.

As Figure 12-1 shows, a bootstrap diode, $D_{BOOTx}$, and a current-limiting resistor, $R_{BOOTx}$, are internally placed in series between the VCC1 and VBx pins.

Time constant for the charging time of $C_{BOOTx}$, $\tau$, can be computed by Equation (3):

$$\tau = C_{BOOTx} \times R_{BOOTx}\ , \tag{3}$$

where $C_{BOOTx}$ is the optimized capacitance of the bootstrap capacitor, and $R_{BOOTx}$ is the resistance of the current-limiting resistor ($60\ \Omega \pm 25\%$).
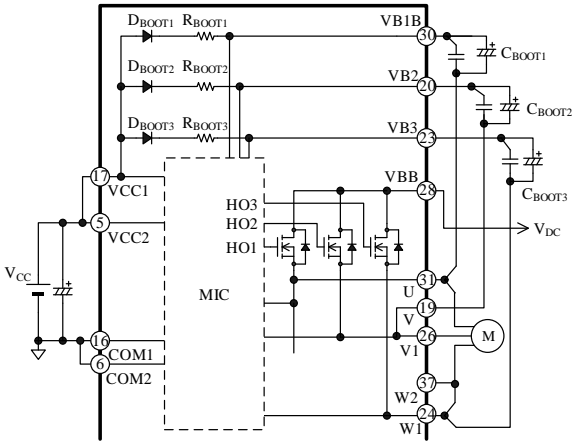
Figure 12-1.　Bootstrap Circuit

Figure 12-2 shows an internal level-shifting circuit. A high-side output signal, HOx, is generated according to an input signal on the HINx pin. When an input signal on the HINx pin transits from low to high (rising edge), a "Set" signal is generated. When the HINx input signal transits from high to low (falling edge), a "Reset" signal is generated. These two signals are then transmitted to the high-side by the level-shifting circuit and are input to the SR flip-flop circuit. Finally, the SR flip-flop circuit feeds an output signal, Q (i.e., HOx).

Figure 12-3 is a timing diagram describing how noise or other detrimental effects will improperly influence the level-shifting process. When a noise-induced rapid voltage drop between the VBx and output pins (U, V, or W1; hereafter "VBx–HSx") occurs after the Set signal generation, the next Reset signal cannot be sent to the SR flip-flop circuit. And the state of an HOx signal stays logic high (or "H") because the SR flip-flop does not respond. With the HOx state being held high (i.e., the high-side transistor is in an on-state), the next LINx signal turns on the low-side transistor and causes a simultaneously-on condition, which may result in critical damage to the IC. To protect the VBx pin against such a noise effect, add a bootstrap capacitor, $C_{BOOTx}$, in each phase. $C_{BOOTx}$ must be placed near the IC and be connected between the VBx and HSx pins with a minimal length of traces. To use an electrolytic capacitor, add a 0.01 μF to 0.1 μF bypass capacitor, $C_{Px}$, in parallel near these pins used for the same phase.
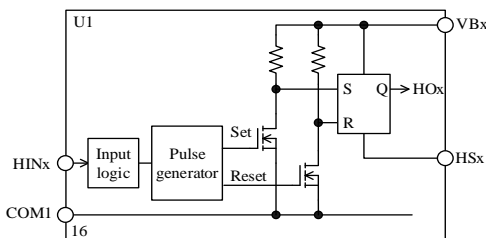


Figure 12-2.　Internal Level-shifting Circuit
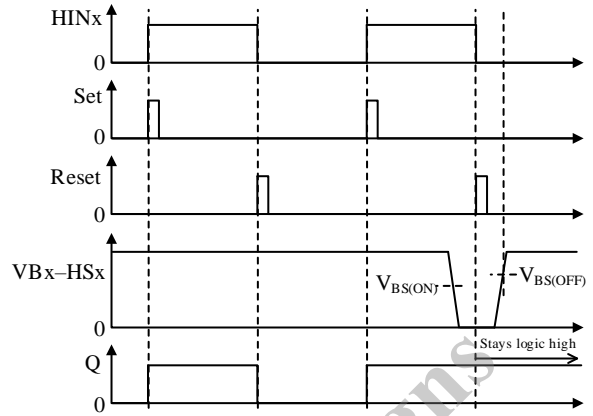


Figure 12-3.　Waveforms at VBx–HSx Voltage Drop

### 12.2.3　VCC1 and VCC2

These are the logic supply pins for the built-in control MIC. The VCC1 and VCC2 pins must be externally connected on a PCB because they are not internally connected. To prevent malfunction induced by supply ripples or other factors, put a 0.01 μF to 0.1 μF ceramic capacitor, $C_{VCC}$, near these pins. To prevent damage caused by surge voltages, put an 18 V to 20 V Zener diode, DZ, between the VCCx and COMx pins.

Voltages to be applied between the VCCx and COMx pins should be regulated within the recommended operational range of $V_{CC}$, given in Section 2.
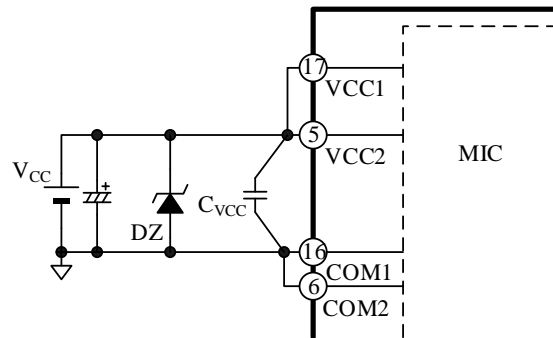


Figure 12-4.　VCCx Pin Peripheral Circuit

### 12.2.4　COM1 and COM2

These are the logic ground pins for the built-in control MIC. The COM1 and COM2 pins should be connected externally on a PCB because they are not internally connected. Varying electric potential of the logic ground can be a cause of improper operations. Therefore, connect the logic ground as close and short as possible to shunt resistors, $R_{Sx}$, at a single-point ground (or star ground) which is separated from the power ground (see Figure
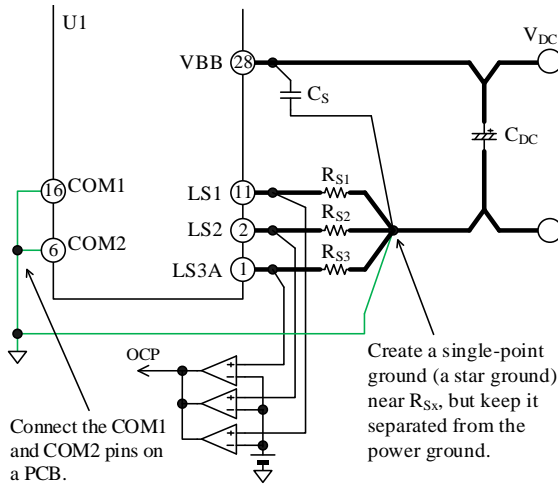
12-5).



Figure 12-5.    Connections to Logic Ground

### 12.2.5   HIN1, HIN2, and HIN3; LIN1, LIN2, and LIN3

These are the input pins of the internal motor drivers for each phase. The HINx pin acts as a high-side controller; the LINx pin acts as a low-side controller.

Figure 12-6 shows an internal circuit diagram of the HINx or LINx pin. This is a CMOS Schmitt trigger circuit with a built-in 20 kΩ pull-down resistor, and its input logic is active high.

Input signals across the HINx–COMx and the LINx–COMx pins in each phase should be set within the ranges provided in Table 12-1, below. Note that dead time setting must be done for HINx and LINx signals because the IC does not have a dead time generator.

The higher PWM carrier frequency rises, the more switching loss increases. Hence, the PWM carrier frequency must be set so that operational case temperatures and junction temperatures have sufficient margins against the absolute maximum ranges, specified in Section 1.

If the signals from the microcontroller become unstable, the IC may result in malfunctions. To avoid this event, the outputs from the microcontroller output line should not be high impedance.

Also, if the traces from the microcontroller to the HINx or LINx pin (or both) are too long, the traces may be interfered by noise. Therefore, it is recommended to add an additional filter or a pull-down resistor near the HINx or LINx pin as needed (see Figure 12-7).

Here are filter circuit constants for reference:
-    $R_{IN1x}$: 33 Ω to 100 Ω
-    $R_{INx}$: 1 kΩ to 10 kΩ
-    $C_{INx}$: 100 pF to 1000 pF

Care should be taken in adding $R_{IN1x}$ and $R_{IN2x}$ to the traces. When they are connected to each other, the input

voltage of the HINx and LINx pins becomes slightly lower than the output voltage of the microcontroller.

Table 12-1.    Input Signals for HINx and LINx Pins

| Parameter | High Level Signal | Low Level Signal |
|---|---|---|
| Input Voltage | 3 V < $V_{IN}$ < 5.5 V | 0 V < $V_{IN}$ < 0.5 V |
| Input Pulse Width | ≥0.5 μs | ≥0.5 μs |
| PWM Carrier Frequency | ≤20 kHz | |
| Dead Time | ≥1.5 μs | |
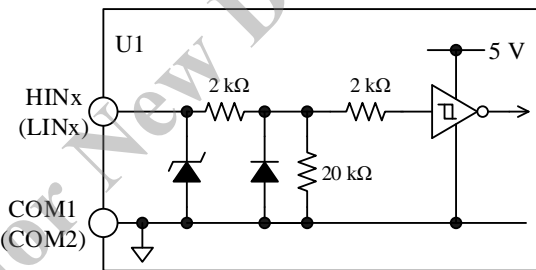


Figure 12-6.    Internal Circuit Diagram of HINx or LINx Pin
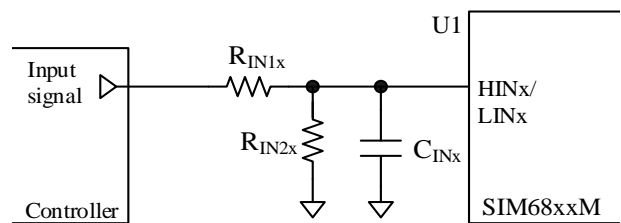


Figure 12-7.    Filter Circuit for HINx or LINx Pin

### 12.2.6   VBB

This is the input pin for the main supply voltage, i.e., the positive DC bus. All of the power MOSFET drains (IGBT collectors) of the high-side are connected to this pin. Voltages between the VBB and COMx pins should be set within the recommended range of the main supply voltage, $V_{DC}$, given in Section 2.

To suppress surge voltages, put a 0.01 μF to 0.1 μF bypass capacitor, $C_S$, near the VBB pin and an electrolytic capacitor, $C_{DC}$, with a minimal length of PCB traces to the VBB pin.

### 12.2.7　LS1, LS2, LS3A, and LS3B

These are the source (emitter) pins of the low-side power MOSFETs (IGBTs). For current detection, the LS1, LS2, and LS3A (LS3B) pins should be externally connected to shunt resistors, $R_{Sx}$. In actual applications, use either of the LS3A or LS3B pin because they are internally connected.

When connecting a shunt resistor, use a resistor with low inductance, and place it as near as possible to the IC with a minimum length of traces to the LSx and COMx pins. The LSx pin may be prone to negative potential due to high inductance, which is mainly caused by longer circuit traces; as a result, circuit malfunctions tend to occur. To avoid such malfunction, design your application so that PCB traces will have inductance as low as possible. In applications where long PCB traces are required, add a fast recovery diode, $D_{RSx}$, between the LSx and COMx pins in order to prevent the IC from malfunctioning. Do not design an application where the LSx Pin Voltage (Surge), $V_{LS(SURGE)}$, decreases to $-4$ V or less.
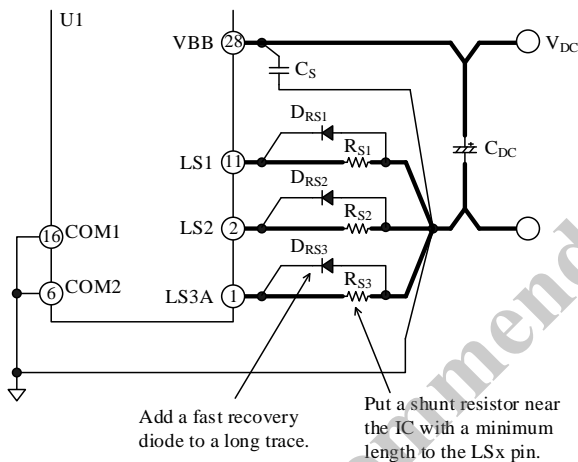


Figure 12-8.　Connections to LSx Pin

### 12.2.8　OCP and OCL

The OCP pin serves as the input for the overcurrent protections which monitor the currents going through the output transistors.

In normal operation, the OCL pin logic level is low. In case one or more of the protections listed below are activated by an OCP input signal, the OCL pin logic level becomes high. If the OCL pin is connected to the SD pin so that the SD pin will respond to the OCL input signal, the high-side transistors can be turned off when the protections (OCP and OCL) are activated.

● **Overcurrent Limit (OCL)**
When the OCP pin voltage exceeds the Current Limit Reference Voltage, $V_{LIM}$, the OCL pin logic level becomes high. While the OCL is in working, the output

transistors operate according to an input signal (HINx or LINx). If the OCL pin is connected to the SD pin, the high-side transistors can be turned off. For a more detailed OCL description, see Section 12.3.4.

● **Overcurrent Pprotection (OCP)**
This function detects inrush currents larger than those detected by the OCL. When the OCP pin voltage exceeds the OCP Threshold Voltage, $V_{TRIP}$, the IC operates as follows: the OCL pin = logic high, the low-side transistors = off, the FO pin = logic low.

In addition, if the OCL pin is connected to the SD pin, the high-side transistors can be turned off. For a more detailed OCP description, see Section 12.3.5.

### 12.2.9　SD

When a 5 V or 3.3 V signal is input to the SD pin, the high-side transistors turn off independently of any HINx signals. This is because the SD pin does not respond to a pulse shorter than an internal filter of 3.3 μs (typ.).

The SD-OCL pin connection, as described in Section 12.2.8, allows the IC to turn off the high-side transistors at OCL or OCP activation. Also, inputting the inverted signal of the FO pin to the SD pin permits all the high- and low-side transistors to turn off, when the IC detects an abnormal condition (i.e., some or all of the protections such as TSD, OCP, and UVLO are activated).

### 12.2.10　FO

This pin operates as the fault signal output and the low-side shutdown signal input. Sections 12.3.1 and 12.3.2 explain the two functions in detail, respectively. Figure 12-9 illustrates an internal circuit diagram of the FO pin and its peripheral circuit.
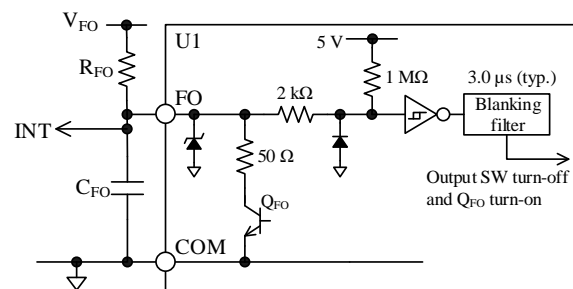


Figure 12-9.　Internal Circuit Diagram of FO Pin and Its Peripheral Circuit

Because of its open-collector nature, the FO pin should be tied by a pull-up resistor, $R_{FO}$, to the external power supply. The external power supply voltage (i.e., the FO Pin Pull-up Voltage, $V_{FO}$) should range from 3.0 V to 5.5 V. When the pull-up resistor, $R_{FO}$, has a too small resistance, the FO pin voltage at fault signal output

becomes high due to the saturation voltage drop of a built-in transistor, $Q_{FO}$. Therefore, it is recommended to use a 3.3 kΩ to 10 kΩ pull-up resistor. To suppress noise, add a filter capacitor, $C_{FO}$, near the IC with minimizing a trace length between the FO and COMx pins.

For avoiding repeated OCP activations, the external microcontroller must shut off any input signals to the IC within an OCP hold time, $t_P$, after the internal transistor ($Q_{FO}$) turn-on. $t_P$ is 15 µs where minimum values of thermal characteristics are taken into account. (For more details, see Section 12.3.5.) Our recommendation is to use a 0.001 µF to 0.01 µF filter capacitor.

## 12.3  Protection Functions

This section describes the various protection circuits provided in the SIM6800M/MV series. The protection circuits include the undervoltage lockout for power supplies (UVLO), the overcurrent protection (OCP), and the thermal shutdown (TSD). In case one or more of these protection circuits are activated, the FO pin outputs a fault signal; as a result, the external microcontroller can stop the operations of the three phases by receiving the fault signal. The external microcontroller can also shut down IC operations by inputting a fault signal to the FO pin.

In the following functional descriptions, "HOx" denotes a gate input signal on the high-side transistor, whereas "LOx" denotes a gate input signal on the low-side transistor.

### 12.3.1  Fault Signal Output

In case one or more of the following protections are actuated, an internal transistor, $Q_{FO}$, turns on, then the FO pin becomes logic low (≤0.5 V).

1) Low-side undervoltage lockout (UVLO_VCC)
2) Overcurrent protection (OCP)
3) Thermal shutdown (TSD)

While the FO pin is in the low state, all the low-side transistors turn off. In normal operation, the FO pin outputs a high signal of about 5 V. Motor operations must be controlled by the external microcontroller so that it can immediately stop the motor when fault signals are detected. To prevent the IC from having permanent damage at OCP activation, be sure to set the motor operation to stop within $t_P$ = 25 µs (typ.). $t_P$ is the fault signal output time of the FO pin, fixed by a built-in feature of the IC itself (see Section 12.3.5). To resume the motor operation thereafter, set the motor to be resumed after a lapse of ≥2 seconds.

### 12.3.2  Shutdown Signal Input

The FO pin also acts as the input pin of shutdown signals. When the FO pin becomes logic low, all the low-side transistors turn off.

The voltages and pulse widths of the shutdown signals to be applied between the FO and COMx pins are listed in Table 12-2.

Table 12-2.  Shutdown Signals

| Parameter | High Level Signal | Low Level Signal |
|---|---|---|
| Input Voltage | 3 V < $V_{IN}$ < 5.5 V | 0 V < $V_{IN}$ < 0.5 V |
| Input Pulse Width | — | ≥6 µs |

### 12.3.3  Undervoltage Lockout for Power Supply (UVLO)

In case the gate-driving voltages of the output transistors decrease, their steady-state power dissipations increase. This overheating condition may cause permanent damage to the IC in the worst case. To prevent this event, the SIM6800M/MV series has the undervoltage lockout (UVLO) circuits for both of the high- and low-side power supplies.

#### 12.3.3.1.  Undervoltage Lockout for High-side Power Supply (UVLO_VB)

Figure 12-10 shows operational waveforms of the undervoltage lockout for high-side power supply (i.e., UVLO_VB).

When the voltage between the VBx and output pins (VBx–HSx shown in Figure 12-10) decreases to the Logic Operation Stop Voltage ($V_{BS(OFF)}$ = 10.0 V) or less, the UVLO_VB circuit in the corresponding phase gets activated and sets an HOx signal to logic low. When the voltage between the VBx and HSx pins increases to the Logic Operation Start Voltage ($V_{BS(ON)}$ = 10.5 V) or more, the IC releases the UVLO_VB operation. Then, the HOx signal becomes logic high at the rising edge of the first input command after the UVLO_VB release. Any fault signals are not output from the FO pin during the UVLO_VB operation. In addition, the VBx pin has an internal UVLO_VB filter of about 3 µs, in order to prevent noise-induced malfunctions.
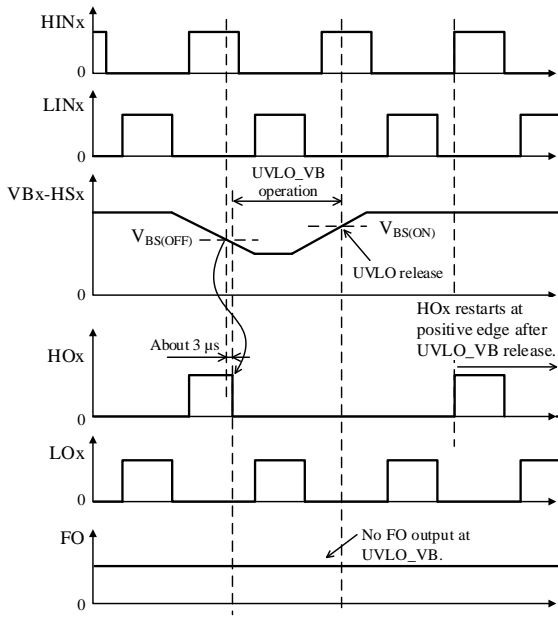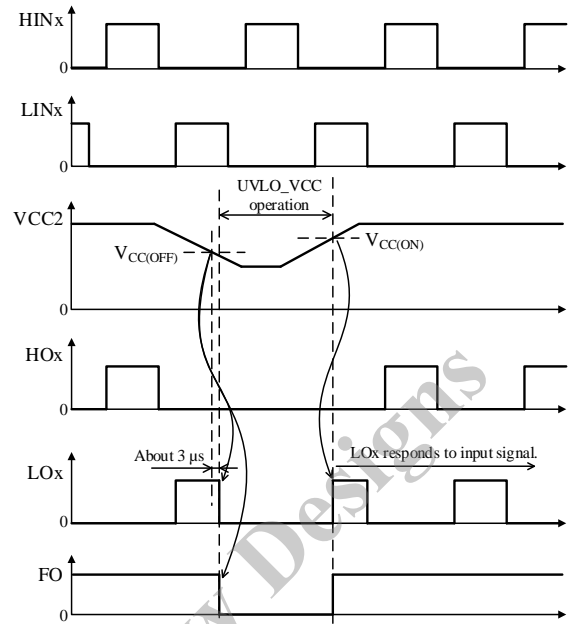
Figure 12-10.   UVLO_VB Operational Waveforms



Figure 12-11.   UVLO_VCC Operational Waveforms

### 12.3.3.2. Undervoltage Lockout for Low-side Power Supply (UVLO_VCC)

Figure 12-11 shows operational waveforms of the undervoltage lockout for low-side power supply (i.e., UVLO_VCC).

When the VCC2 pin voltage decreases to the Logic Operation Stop Voltage ($V_{CC(OFF)}$ = 11.0 V) or less, the UVLO_VCC circuit in the corresponding phase gets activated and sets both of HOx and LOx signals to logic low. When the VCC2 pin voltage increases to the Logic Operation Start Voltage ($V_{CC(ON)}$ = 11.5 V) or more, the IC releases the UVLO_VCC operation. Then, the IC resumes the following transmissions: an LOx signal according to an LINx pin input command; an HOx signal according to the rising edge of the first HINx pin input command after the UVLO_VCC release. During the UVLO_VCC operation, the FO pin becomes logic low and sends fault signals. In addition, the VCC2 pin has an internal UVLO_VCC filter of about 3 μs, in order to prevent noise-induced malfunctions.

### 12.3.4   Overcurrent Limit (OCL)

The overcurrent limit (OCL) is a protection against relatively low overcurrent conditions. Figure 12-12 shows an internal circuit of the OCP and OCL pins; Figure 12-13 shows OCL operational waveforms.

When the OCP pin voltage increases to the Current Limit Reference Voltage ($V_{LIM}$ = 0.6500 V) or more, and remains in this condition for a period of the Current Limit Blanking Time ($t_{BK(OCP)}$ = 2 μs) or longer, the OCL circuit is activated. Then, the OCL pin goes logic high.

During the OCL operation, the gate logic levels of the low-side transistors respond to an input command on the LINx pin. To turn off the high-side transistors during the OCL operation, connect the OCL and SD pins on a PCB. The SD pin has an internal filter of about 3.3 μs (typ.).

When the OCP pin voltage falls below $V_{LIM}$ (0.6500 V), the OCL pin logic level becomes low. After the OCL pin logic has become low, the high-side transistors remain turned off until the first low-to-high transition on an HINx input signal occurs (i.e., edge-triggered).
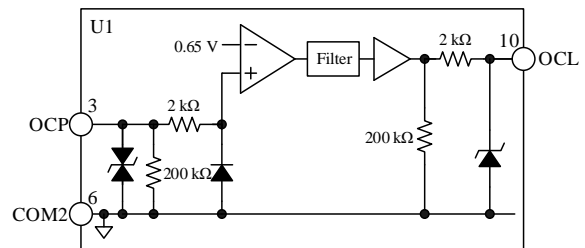


Figure 12-12.   Internal Circuit of OCP and OCL Pins
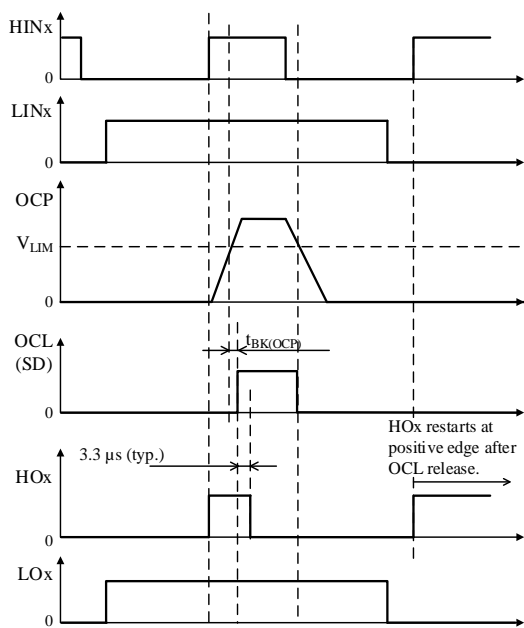
Figure 12-13.   OCL Operational Waveforms
(OCL = SD)

### 12.3.5   Overcurrent Protection (OCP)

The overcurrent protection (OCP) is a protection against large inrush currents (i.e., high di/dt). Figure 12-14 is an internal circuit diagram describing the OCP pin and its peripheral circuit.

The OCP pin detects overcurrents with voltage across external shunt resistors, $R_{Sx}$. Because the OCP pin is internally pulled down, the OCP pin voltage increases proportionally to a rise in the currents running through the shunt resistors, $R_{Sx}$.
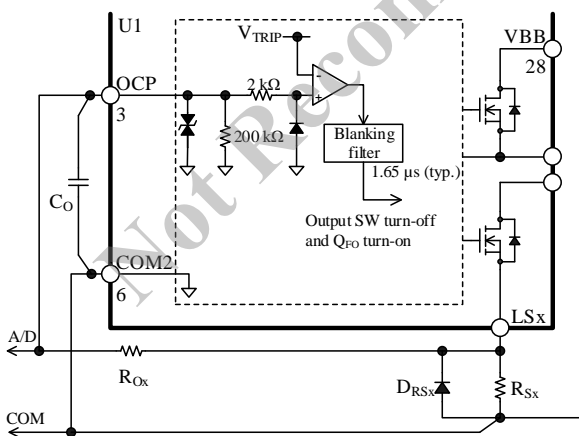


Figure 12-14.   Internal Circuit Diagram of OCP Pin and Its Peripheral Circuit



Figure 12-15.   OCP Operational Waveforms

Figure 12-15 is a timing chart that represents operation waveforms during OCP operation. When the OCP pin voltage increases to the OCP Threshold Voltage ($V_{TRIP} = 1.0$ V) or more, and remains in this condition for a period of the OCP Blanking Time ($t_{BK} = 2$ μs) or longer, the OCP circuit is activated. The enabled OCP circuit shuts off the low-side transistors and puts the FO pin into a low state. Then, output current decreases as a result of the output transistor turn-offs. Even if the OCP pin voltage falls below $V_{TRIP}$, the IC holds the FO pin in the low state for a fixed OCP hold time, $t_P = 25$ μs (typ.). Then, the output transistors operate according to input signals.

The OCP is used for detecting abnormal conditions, such as an output transistor shorted. In case short-circuit conditions occur repeatedly, the output transistors can be destroyed. For this reason, motor operations must be controlled by the external microcontroller so that it can immediately stop the motor when fault signals are detected.

For proper shunt resistor setting, your application must meet the following:

● Use the shunt resistor that has a recommended resistance, $R_{Sx}$ (see Section 2).
● Set the OCP pin input voltage to vary within the rated OCP pin voltages, $V_{OCP}$ (see Section 1).
● Keep the current through the output transistors below the rated output current (pulse), $I_{OP}$ (see Section 1).

It is required to use a resistor with low internal inductance because high-frequency switching current will flow through the shunt resistors, $R_{Sx}$. In addition, choose a resistor with allowable power dissipation according to your application.

When you connect a CR filter (i.e., a pair of a filter resistor, $R_O$, and a filter capacitor, $C_O$) to the OCP pin,

care should be taken in setting the time constants of $R_O$ and $C_O$. The larger the time constant, the longer the time that the OCP pin voltage rises to $V_{TRIP}$. And this may cause permanent damage to the transistors. Consequently, a propagation delay of the IC must be taken into account when you determine the time constants. For $R_O$ and $C_O$, their time constants must be set to the values listed in Table 12-3. And place $C_O$ as close as possible to the IC with minimizing a trace length between the OCP and COMx pins.

Note that overcurrents are undetectable when one or more of the U, V/V1/V2, and W1/W2 pins or their traces are shorted to ground (ground fault). In case any of these pins falls into a state of ground fault, the output transistors may be destroyed.

Table 12-3. Reference Time Constants for CR Filter

| Part Number | Time Constant (µs) |
|---|---|
| SIM6811M SIM6812M | ≤2 |
| SIM6822MV SIM6880M | ≤0.2 |

### 12.3.6 Thermal Shutdown (TSD)

The SIM6800M/MV series incorporates the thermal shutdown (TSD) circuit. Figure 12-16 shows TSD operational waveforms. In case of overheating (e.g., increased power dissipation due to overload, or elevated ambient temperature at the device), the IC shuts down the low-side output transistors.

The TSD circuit in the MIC monitors temperatures (see Section 7). When the temperature of the MIC exceeds the TSD Operating Temperature ($T_{DH}$ = 150 °C), the TSD circuit is activated.

When the temperature of the MIC decreases to the TSD Releasing Temperature ($T_{DL}$ = 120 °C) or less, the shutdown condition is released. The output transistors then resume operating according to input signals.

During the TSD operation, the FO pin becomes logic low and transmits fault signals.

Note that junction temperatures of the output transistors themselves are not monitored; therefore, do not use the TSD function as an overtemperature prevention for the output transistors.



Figure 12-16. TSD Operational Waveforms

## 13. Design Notes

### 13.1 PCB Pattern Layout

Figure 13-1 shows a schematic diagram of a motor drive circuit. The circuit consists of current paths having high frequencies and high voltages, which also bring about negative influences on IC operation, noise interference, and power dissipation. Therefore, PCB trace layouts and component placements play an important role in circuit designing.

Current loops, which have high frequencies and high voltages, should be as small and wide as possible, in order to maintain a low-impedance state. In addition, ground traces should be as wide and short as possible so that radiated EMI levels can be reduced.
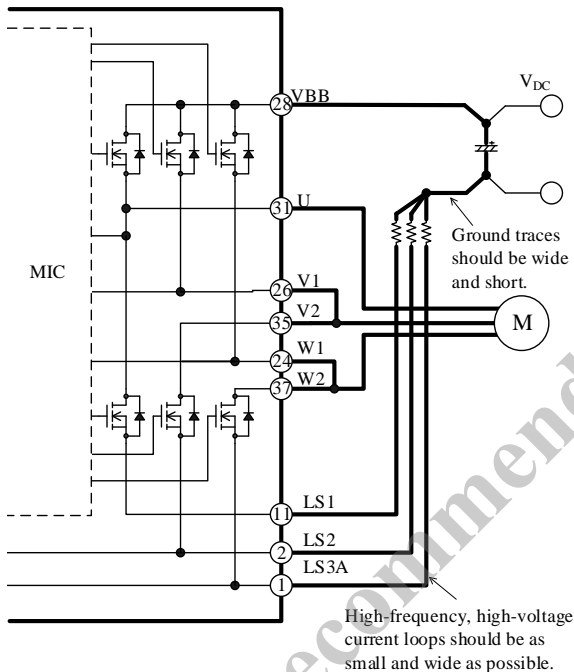


Figure 13-1.   High-frequency, High-voltage Current Paths

### 13.2 Considerations in Heatsink Mounting

The following are the key considerations and the guidelines for mounting a heatsink:

● Be sure to use a metric screw of M2.5 and a plain washer of 6.0 mm (φ). When tightening the screws, use a torque screwdriver and tighten them within the range of screw torque defined in Section 4. Be sure to avoid uneven tightening. Temporarily tighten the two screws first, then tighten them equally on both sides until the specified screw torque is reached.

● When mounting a heatsink, it is recommended to use silicone greases. If a thermally conductive sheet or an

electrically insulating sheet is used, package cracks may be occurred due to creases at screw tightening. Therefore, you should conduct thorough evaluations before using these materials.

● When applying a silicone grease, make sure that there are no foreign substances between the IC and a heatsink. Extreme care should be taken not to apply a silicone grease onto any device pins as much as possible. The following requirements must be met for proper grease application:

- Grease thickness: 100 μm
- Heatsink flatness: ±100 μm
- Apply silicone grease within the area indicated in Figure 13-2, below.
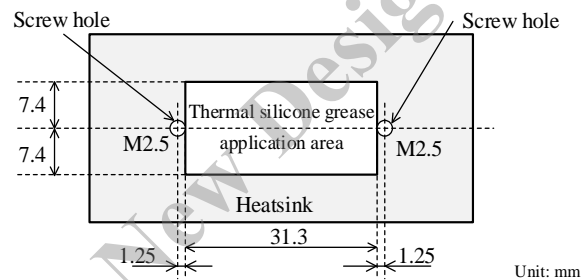


Figure 13-2.   Reference Application Area for Thermal Silicone Grease

### 13.3 Considerations in IC Characteristics Measurement

When measuring the breakdown voltage or leakage current of the transistors incorporated in the IC, note that the gate and source (emitter) of each transistor should have the same potential. Moreover, care should be taken during the measurement because each transistor is connected as follows:

● All the high-side drains (collectors) are internally connected to the VBB pin.

● In the U-phase, the high-side source (emitter) and the low-side drain (collector) are internally connected, and are also connected to the U pin.
(In the V- and W-phases, the high- and low-side transistors are unconnected inside the IC.)

The gates of the high-side transistors are pulled down to the corresponding output (U, V/V1, and W1) pins; similarly, the gates of the low-side transistors are pulled down to the COM2 pin.

When measuring the breakdown voltage or leakage current of the transistors, note that all of the output (U, V/V1, and W1), LSx, and COMx pins must be appropriately connected. Otherwise, the switching transistors may result in permanent damage.

The following are circuit diagrams representing typical measurement circuits for breakdown voltage: Figure 13-3 shows the high-side transistor ($Q_{1H}$) in the U-phase;

Figure 13-4 shows the low-side transistor ($Q_{1L}$) in the U-phase. And all the pins that are not represented in these figures are open.

When measuring the high-side transistors, leave all the non-measuring pins open. When measuring the low-side transistors, connect only the measuring LSx pin to the COMx pin and leave the other pins open.
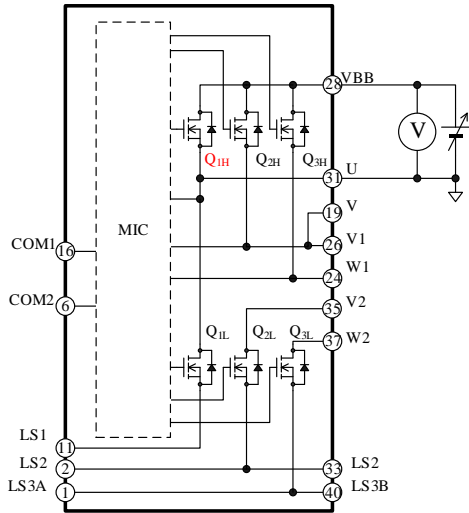


Figure 13-3.    Typical Measurement Circuit for High-side Transistor ($Q_{1H}$) in U-phase
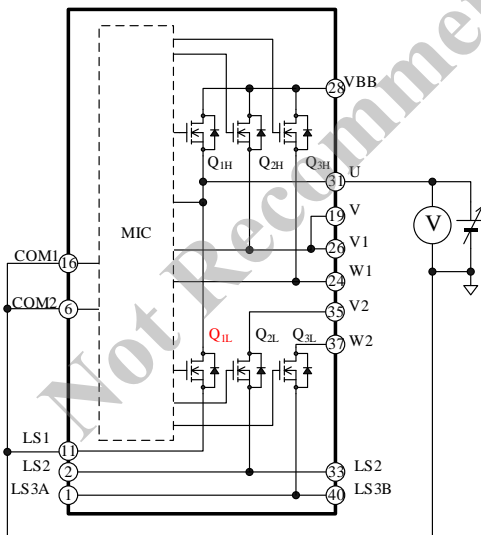


Figure 13-4.    Typical Measurement Circuit for Low-side Transistor ($Q_{1L}$) in U-phase

# 14.    Calculating Power Losses and Estimating Junction Temperatures

This section describes the procedures to calculate power losses in switching transistors, and to estimate a junction temperature. Note that the descriptions listed here are applicable to the SIM6800M/MV series, which is controlled by a 3-phase sine-wave PWM driving strategy.

For quick and easy references, we offer calculation support tools online. Please visit our website to find out more.

● DT0050: Motor Driver ICs (with MOSFETs) Power Loss Calculation Tool
http://www.semicon.sanken-ele.co.jp/en/calc-tool/mosfet_caltool_en.html

● DT0052: Motor Driver ICs (with IGBTs) Power Loss Calculation Tool
http://www.semicon.sanken-ele.co.jp/en/calc-tool/igbtall_caltool_en.html

## 14.1    IGBT

Total power loss in an IGBT can be obtained by taking the sum of steady-state loss, $P_{ON}$, and switching loss, $P_{SW}$. The following subsections contain the mathematical procedures to calculate these losses ($P_{ON}$ and $P_{SW}$) and the junction temperature of all IGBTs operating.

### 14.1.1    IGBT Steady-state Loss, $P_{ON}$

Steady-state loss in an IGBT can be computed by using the $V_{CE(SAT)}$ vs. $I_C$ curves, listed in Section 15.3.1. As expressed by the curves in Figure 14-1, a linear approximation at a range the $I_C$ is actually used is obtained by: $V_{CE(SAT)} = \alpha \times I_C + \beta$. The values gained by the above calculation are then applied as parameters in Equation (4), below. Hence, the equation to obtain the IGBT steady-state loss, $P_{ON}$, is:

$$P_{ON} = \frac{1}{2\pi} \int_0^\pi V_{CE(SAT)}(\varphi) \times I_C(\varphi) \times DT \times d\varphi$$

$$= \frac{1}{2}\alpha\left(\frac{1}{2} + \frac{4}{3\pi}M \times \cos\theta\right)I_M{}^2$$
$$+ \frac{\sqrt{2}}{\pi}\beta\left(\frac{1}{2} + \frac{\pi}{8}M \times \cos\theta\right)I_M . \tag{4}$$

Where:

$V_{CE(SAT)}$ is the collector-to-emitter saturation voltage of the IGBT (V),

$I_C$ is the collector current of the IGBT (A),

DT is the duty cycle, which is given by

$$DT = \frac{1 + M \times \sin(\varphi + \theta)}{2} ,$$

M is the modulation index (0 to 1),
$\cos\theta$ is the motor power factor (0 to 1),
$I_M$ is the effective motor current (A),
$\alpha$ is the slope of the linear approximation in the $V_{CE(SAT)}$ vs. $I_C$ curve, and
$\beta$ is the intercept of the linear approximation in the $V_{CE(SAT)}$ vs. $I_C$ curve.
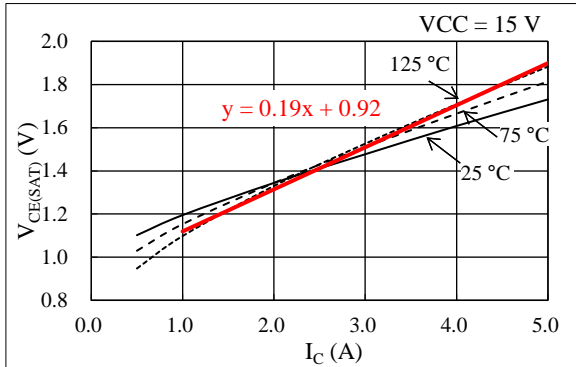


Figure 14-1.    Linear Approximate Equation of $V_{CE(SAT)}$ vs. $I_C$

### 14.1.2   IGBT Switching Loss, $P_{SW}$

Switching loss in an IGBT can be calculated by Equation (5), letting $I_M$ be the effective current value of the motor:

$$P_{SW} = \frac{\sqrt{2}}{\pi} \times f_C \times \alpha_E \times I_M \times \frac{V_{DC}}{300} . \tag{5}$$

Where:
$f_C$ is the PWM carrier frequency (Hz),
$V_{DC}$ is the main power supply voltage (V), i.e., the VBB pin input voltage, and
$\alpha_E$ is the slope of the switching loss curve (see Section 15.3.2).

### 14.1.3   Estimating Junction Temperature of IGBT

The junction temperature of all IGBTs operating, $T_J$, can be estimated with Equation (6):

$$T_J = R_{(J-C)Q} \times \{(P_{ON} + P_{SW}) \times 6\} + T_C . \tag{6}$$

Where:
$R_{(J-C)Q}$ is the junction-to-case thermal resistance (°C/W) of all the IGBTs operating, and
$T_C$ is the case temperature (°C), measured at the point defined in Figure 3-1.

## 14.2   Power MOSFET

Total power loss in a power MOSFET can be obtained by taking the sum of the following losses: steady-state loss, $P_{RON}$; switching loss, $P_{SW}$; the steady-state loss of a body diode, $P_{SD}$. In the calculation procedure we offer, the recovery loss of a body diode, $P_{RR}$, is considered negligibly small compared with the ratios of other losses.

The following subsections contain the mathematical procedures to calculate these losses ($P_{RON}$, $P_{SW}$, and $P_{SD}$) and the junction temperature of all power MOSFETs operating.

### 14.2.1   Power MOSFET Steady-state Loss, $P_{RON}$

Steady-state loss in a power MOSFET can be computed by using the $R_{DS(ON)}$ vs. $I_D$ curves, listed in Section 15.3.1. As expressed by the curves in Figure 14-2, a linear approximation at a range the $I_D$ is actually used is obtained by: $R_{DS(ON)} = \alpha \times I_D + \beta$. The values gained by the above calculation are then applied as parameters in Equation (7), below. Hence, the equation to obtain the power MOSFET steady-state loss, $P_{RON}$, is:

$$
\begin{aligned}
P_{RON} &= \frac{1}{2\pi} \int_0^\pi I_D\,(\varphi)^2 \times R_{DS(ON)}(\varphi) \times DT \times d\varphi \\
&= 2\sqrt{2}\alpha \left( \frac{1}{3\pi} + \frac{3}{32} M \times \cos\theta \right) I_M{}^3 \\
&\quad + 2\beta \left( \frac{1}{8} + \frac{1}{3\pi} M \times \cos\theta \right) I_M{}^2 .
\end{aligned}
\tag{7}
$$

Where:
$I_D$ is the drain current of the power MOSFET (A),
$R_{DS(ON)}$ is the drain-to-source on-resistance of the power MOSFET (Ω),
DT is the duty cycle, which is given by

$$DT = \frac{1 + M \times \sin(\varphi + \theta)}{2} ,$$

M is the modulation index (0 to 1),
$\cos\theta$ is the motor power factor (0 to 1),
$I_M$ is the effective motor current (A),
$\alpha$ is the slope of the linear approximation in the $R_{DS(ON)}$ vs. $I_D$ curve, and
$\beta$ is the intercept of the linear approximation in the $R_{DS(ON)}$ vs. $I_D$ curve.
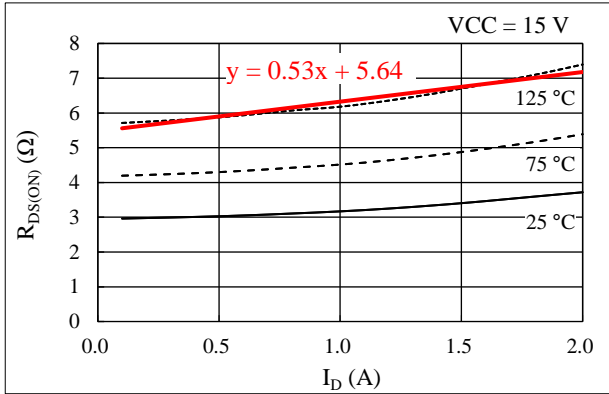
Figure 14-2.   Linear Approximate Equation of $R_{DS(ON)}$) vs. $I_D$

### 14.2.2   Power MOSFET Switching Loss, $P_{SW}$

Switching loss in a power MOSFET can be calculated by Equation (8), letting $I_M$ be the effective current value of the motor:

$$P_{SW} = \frac{\sqrt{2}}{\pi} \times f_C \times \alpha_E \times I_M \times \frac{V_{DC}}{300} . \quad (8)$$

Where:
  $f_C$ is the PWM carrier frequency (Hz),
  $V_{DC}$ is the main power supply voltage (V), i.e., the VBB pin input voltage, and
  $\alpha_E$ is the slope of the switching loss curve (see Section 15.3.2).

### 14.2.3   Body Diode Steady-state Loss, $P_{SD}$

Steady-state loss in the body diode of a power MOSFET can be computed by using the $V_{SD}$ vs. $I_{SD}$ curves, listed in Section 15.3.1. As expressed by the curves in Figure 14-3, a linear approximation at a range the $I_{SD}$ is actually used is obtained by: $V_{SD} = \alpha \times I_{SD} + \beta$. The values gained by the above calculation are then applied as parameters in Equation (9), below. Hence, the equation to obtain the body diode steady-state loss, $P_{SD}$, is:

$$P_{SD} = \frac{1}{2\pi} \int_0^\pi V_{SD}(\varphi) \times I_{SD}(\varphi) \times (1 - DT) \times d\varphi$$

$$= \frac{1}{2} \alpha \left( \frac{1}{2} - \frac{4}{3\pi} M \times \cos\theta \right) I_M{}^2$$
$$+ \frac{\sqrt{2}}{\pi} \beta \left( \frac{1}{2} - \frac{\pi}{8} M \times \cos\theta \right) I_M \quad (9)$$

Where:
  $V_{SD}$ is the source-to-drain diode forward voltage of the power MOSFET (V),
  $I_{SD}$ is the source-to-drain diode forward current of the power MOSFET (A),
  DT is the duty cycle, which is given by

$$DT = \frac{1 + M \times \sin(\varphi + \theta)}{2} ,$$

  M is the modulation index (0 to 1),
  $\cos\theta$ is the motor power factor (0 to 1),
  $I_M$ is the effective motor current (A),
  $\alpha$ is the slope of the linear approximation in the $V_{SD}$ vs. $I_{SD}$ curve, and
  $\beta$ is the intercept of the linear approximation in the $V_{SD}$ vs. $I_{SD}$ curve.
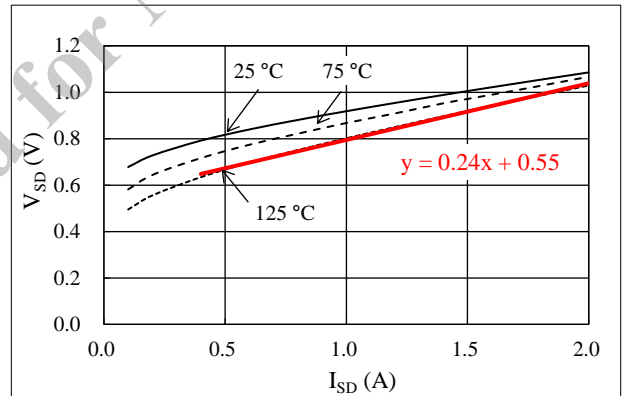


Figure 14-3.   Linear Approximate Equation of $V_{SD}$ vs. $I_{SD}$

### 14.2.4   Estimating Junction Temperature of Power MOSFET

The junction temperature of all power MOSFETs operating, $T_J$, can be estimated with Equation (10):

$$T_J = R_{J-C} \times \{(P_{ON} + P_{SW} + P_{SD}) \times 6\} + T_C . \quad (10)$$

Where:
  $R_{J-C}$ is the junction-to-case thermal resistance (°C/W) of all the power MOSFETs operating, and
  $T_C$ is the case temperature (°C), measured at the point defined in Figure 3-1.

## 15. Performance Curves

### 15.1 Transient Thermal Resistance Curves

The following graphs represent transient thermal resistance (the ratios of transient thermal resistance), with steady-state junction-to-case thermal resistance = 1. Note that the graph representing that of the IGBT-embedded device shows only IGBT characteristics; no freewheeling diode characteristics are included.
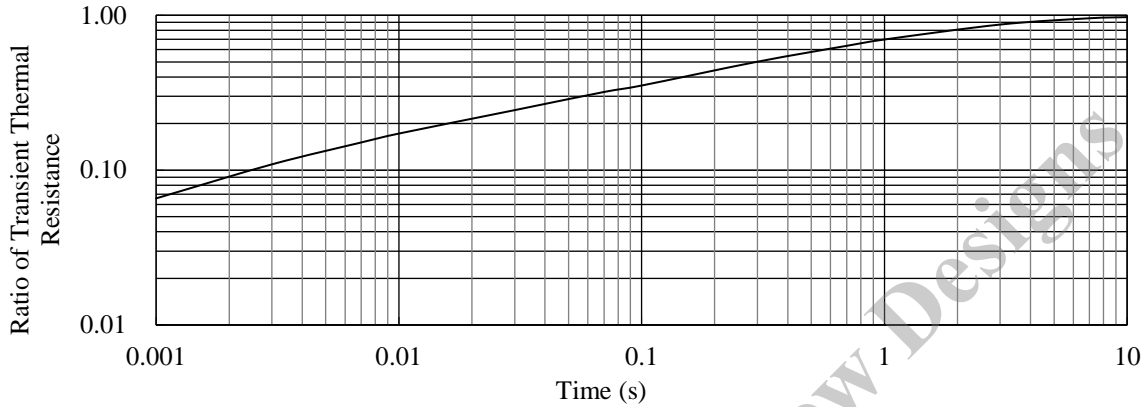
Figure 15-1.   Transient Thermal Resistance: SIM6811M, SIM6812M
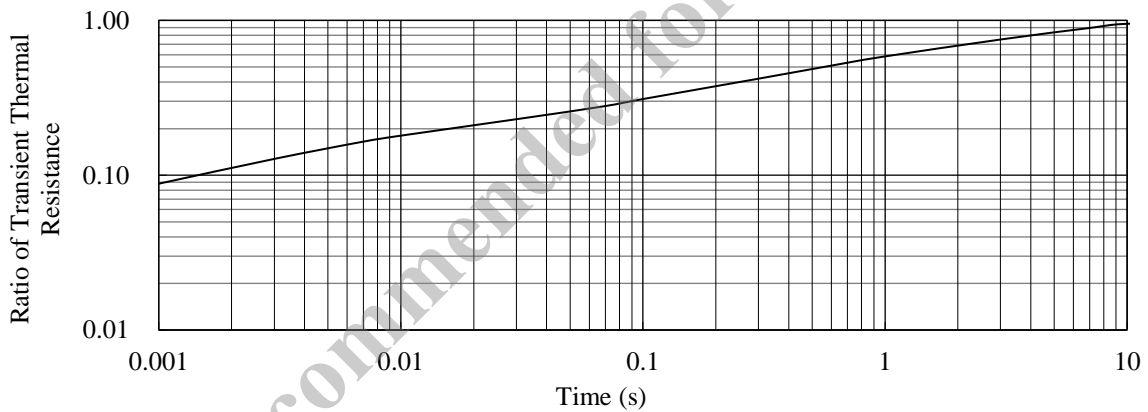
Figure 15-2.   Transient Thermal Resistance: SIM6822MV
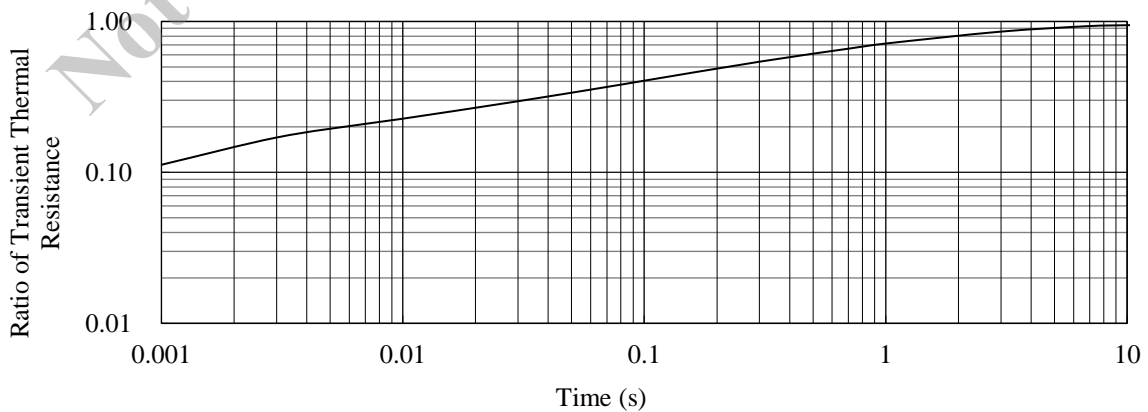
Figure 15-3.   Transient Thermal Resistance: SIM6880M

## 15.2 Performance Curves of Control Parts

Figure 15-4 to Figure 15-28 provide performance curves of the control parts integrated in the SIM6800M/MV series, including variety-dependent characteristics and thermal characteristics. $T_J$ represents the junction temperature of the control parts.

Table 15-1.　Typical Characteristics of Control Parts

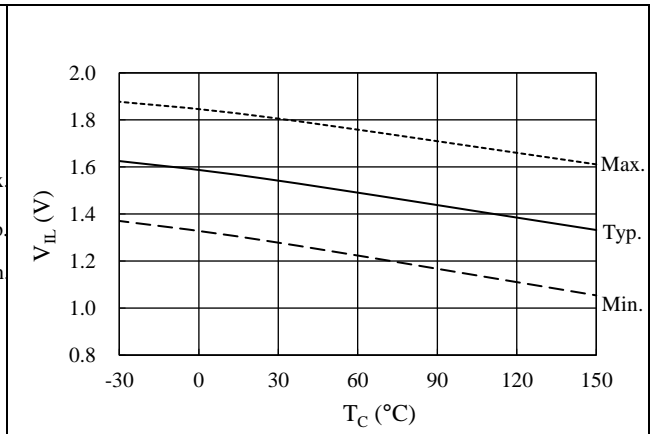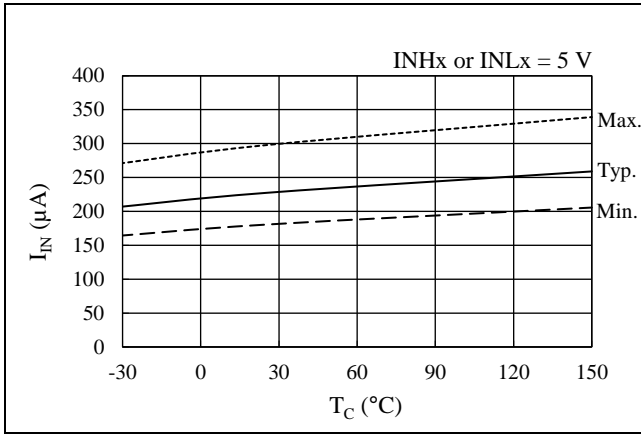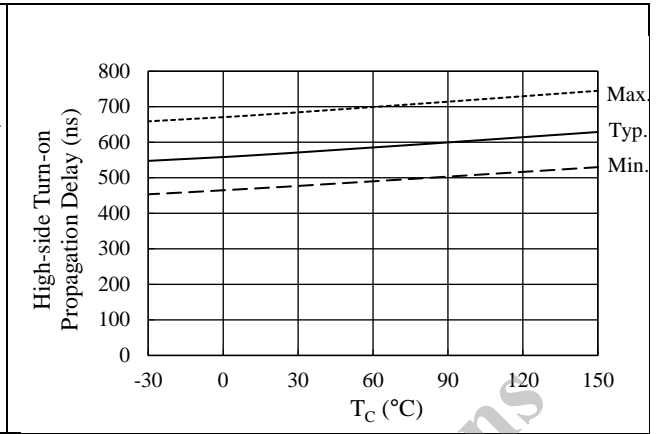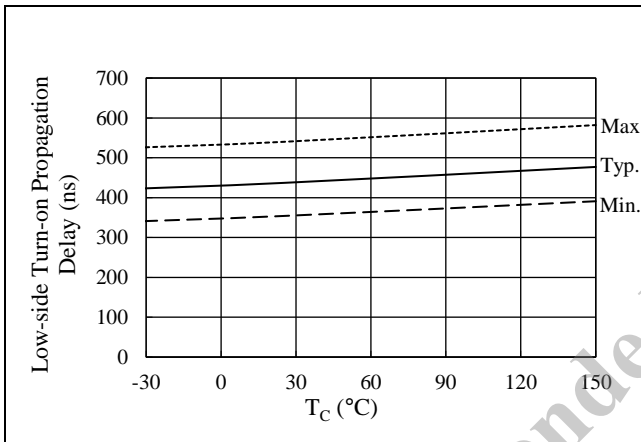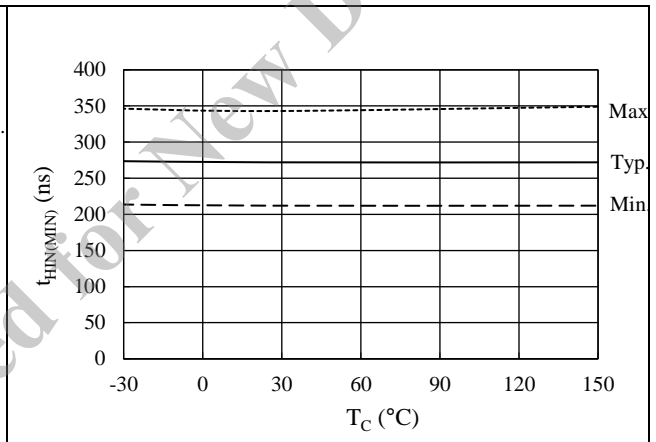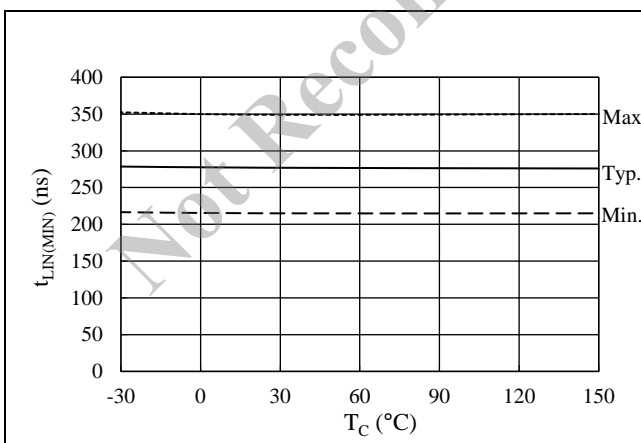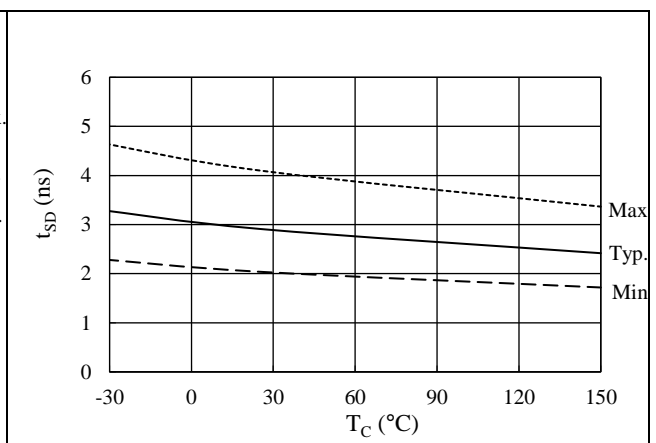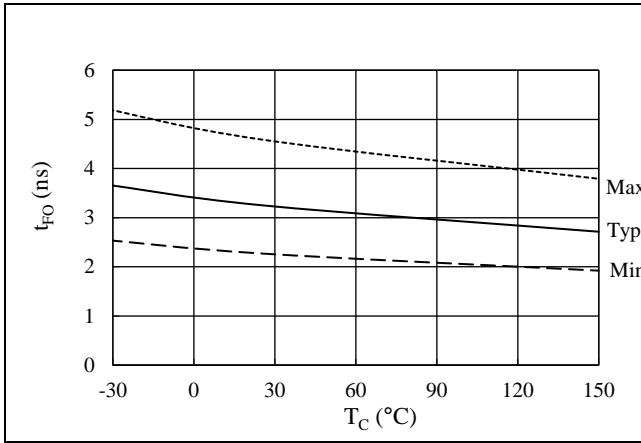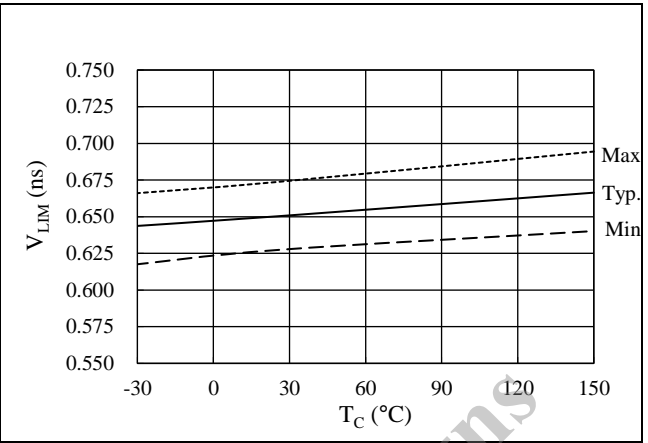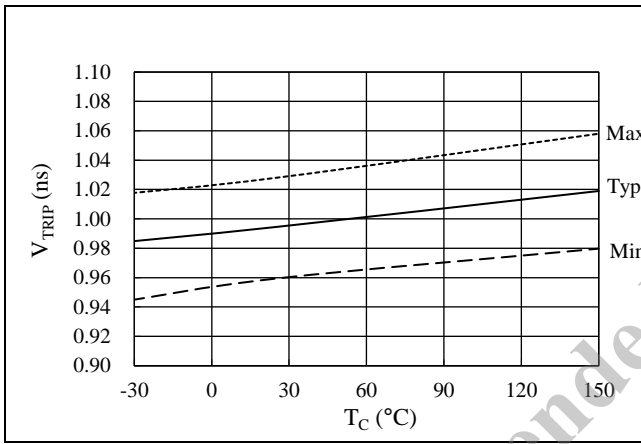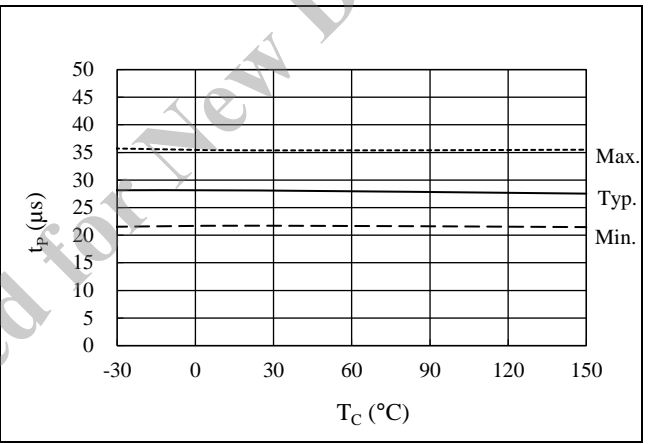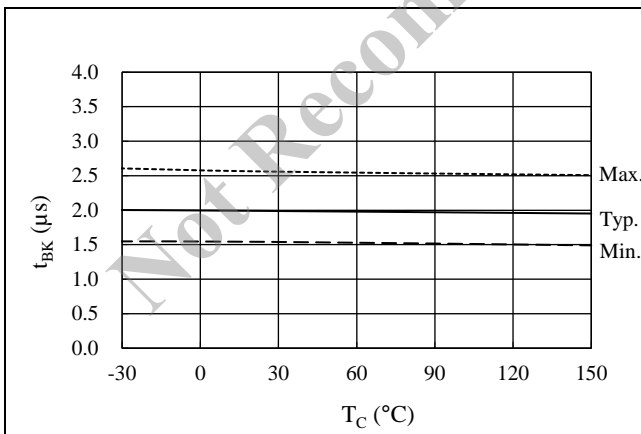| Figure Number | Figure Caption |
|---|---|
| Figure 15-4 | Logic Supply Current, $I_{CC}$ vs. $T_C$ (INx = 0 V) |
| Figure 15-5 | Logic Supply Current, $I_{CC}$ vs. $T_C$ (INx = 5 V) |
| Figure 15-6 | VCCx Pin Voltage, $V_{CC}$ vs. Logic Supply Current, $I_{CC}$ |
| Figure 15-7 | Logic Supply Current (1-phase) $I_{BS}$ vs. $T_C$ (HINx = 0 V) |
| Figure 15-8 | Logic Supply Current (1-phase) $I_{BS}$ vs. $T_C$ (HINx = 5 V) |
| Figure 15-9 | VBx Pin Voltage, $V_B$ vs. Logic Supply Current, $I_{BS}$ (HINx = 0 V) |
| Figure 15-10 | Logic Operation Start Voltage, $V_{BS(ON)}$ vs. $T_C$ |
| Figure 15-11 | Logic Operation Stop Voltage, $V_{BS(OFF)}$ vs. $T_C$ |
| Figure 15-12 | Logic Operation Start Voltage, $V_{CC(ON)}$ vs. $T_C$ |
| Figure 15-13 | Logic Operation Stop Voltage, $V_{CC(OFF)}$ vs. $T_C$ |
| Figure 15-14 | UVLO_VB Filtering Time vs. $T_C$ |
| Figure 15-15 | UVLO_VCC Filtering Time vs. $T_C$ |
| Figure 15-16 | High Level Input Threshold Voltage, $V_{IH}$ vs. $T_C$ |
| Figure 15-17 | Low Level Input Threshold Voltage, $V_{IL}$ vs. $T_C$ |
| Figure 15-18 | Input Current at High Level (HINx or LINx), $I_{IN}$ vs. $T_C$ |
| Figure 15-19 | High-side Turn-on Propagation Delay vs. $T_C$ (from HINx to HOx) |
| Figure 15-20 | Low-side Turn-on Propagation Delay vs. $T_C$ (from LINx to LOx) |
| Figure 15-21 | Minimum Transmittable Pulse Width for High-side Switching, $t_{HIN(MIN)}$ vs. $T_C$ |
| Figure 15-22 | Minimum Transmittable Pulse Width for Low-side Switching, $t_{LIN(MIN)}$ vs. $T_C$ |
| Figure 15-23 | SD Pin Filtering Time vs. $T_C$ |
| Figure 15-24 | FO Pin Filtering Time vs. $T_C$ |
| Figure 15-25 | Current Limit Reference Voltage, $V_{LIM}$ vs. $T_C$ |
| Figure 15-26 | OCP Threshold Voltage, $V_{TRIP}$ vs. $T_C$ |
| Figure 15-27 | OCP Hold Time, $t_P$ vs. $T_C$ |
| Figure 15-28 | OCP Blanking Time, $t_{BK(OCP)}$ vs. $T_C$; Current Limit Blanking Time, $t_{BK(OCL)}$ vs. $T_C$ |



Figure 15-4.　Logic Supply Current, $I_{CC}$ vs. $T_C$ (INx = 0 V)

Figure 15-5.　Logic Supply Current, $I_{CC}$ vs. $T_C$ (INx = 5 V)

Figure 15-6.   VCCx Pin Voltage, $V_{CC}$ vs. Logic Supply Current, $I_{CC}$



Figure 15-7.   Logic Supply Current (1-phase) $I_{BS}$ vs. $T_C$ (HINx = 0 V)



Figure 15-8.   Logic Supply Current (1-phase) $I_{BS}$ vs. $T_C$ (HINx = 5 V)



Figure 15-9.   VBx Pin Voltage, $V_B$ vs. Logic Supply Current, $I_{BS}$ (HINx = 0 V)



Figure 15-10.   Logic Operation Start Voltage, $V_{BS(ON)}$ vs. $T_C$



Figure 15-11.   Logic Operation Stop Voltage, $V_{BS(OFF)}$ vs. $T_C$

Figure 15-12.   Logic Operation Start Voltage, $V_{CC(ON)}$ vs. $T_C$



Figure 15-13.   Logic Operation Stop Voltage, $V_{CC(OFF)}$ vs. $T_C$



Figure 15-14.   UVLO_VB Filtering Time vs. $T_C$



Figure 15-15.   UVLO_VCC Filtering Time vs. $T_C$



Figure 15-16.   High Level Input Threshold Voltage, $V_{IH}$ vs. $T_C$



Figure 15-17.   Low Level Input Threshold Voltage, $V_{IL}$ vs. $T_C$

Figure 15-18.   Input Current at High Level (HINx or LINx), $I_{IN}$ vs. $T_C$

Figure 15-19.   High-side Turn-on Propagation Delay vs. $T_C$ (from HINx to HOx)

Figure 15-20.   Low-side Turn-on Propagation Delay vs. $T_C$ (from LINx to LOx)

Figure 15-21.   Minimum Transmittable Pulse Width for High-side Switching, $t_{HIN(MIN)}$ vs. $T_C$

Figure 15-22.   Minimum Transmittable Pulse Width for Low-side Switching, $t_{LIN(MIN)}$ vs. $T_C$

Figure 15-23.   SD Pin Filtering Time vs. $T_C$

Figure 15-24.    FO Pin Filtering Time vs. T_C



Figure 15-25.    Current Limit Reference Voltage, V_LIM vs. T_C



Figure 15-26.    OCP Threshold Voltage, V_TRIP vs. T_C



Figure 15-27.    OCP Hold Time, t_P vs. T_C



Figure 15-28.    OCP Blanking Time, t_BK(OCP) vs. T_C; Current Limit Blanking Time, t_BK(OCL) vs. T_C

## 15.3 Performance Curves of Output Parts

### 15.3.1 Output Transistor Performance Curves

#### 15.3.1.1. SIM6811M
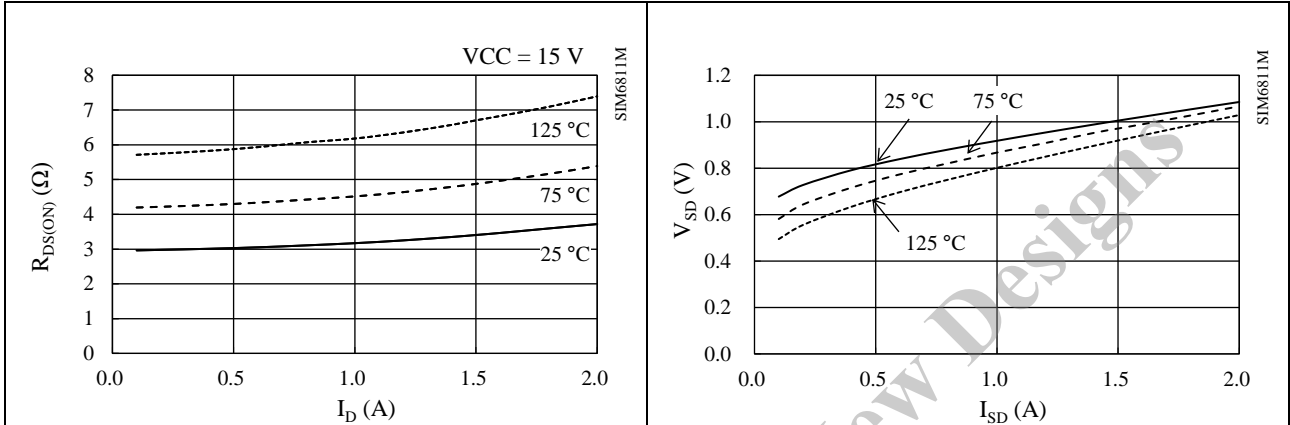


Figure 15-29.   Power MOSFET $R_{DS(ON)}$ vs. $I_D$



Figure 15-30.   Power MOSFET $V_{SD}$ vs. $I_{SD}$

#### 15.3.1.2. SIM6812M
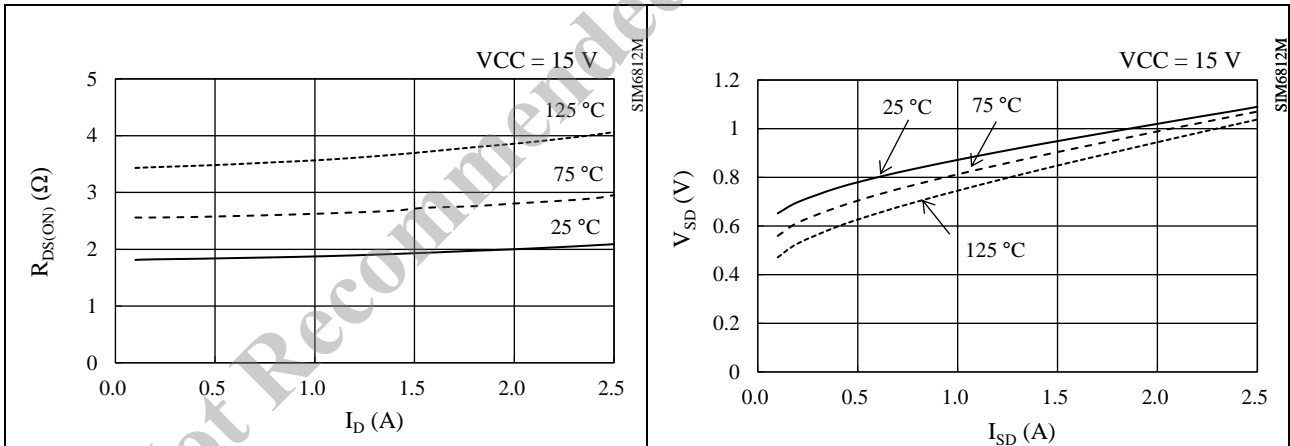


Figure 15-31.   Power MOSFET $R_{DS(ON)}$ vs. $I_D$



Figure 15-32.   Power MOSFET $V_{SD}$ vs. $I_{SD}$

### 15.3.1.3. SIM6880M
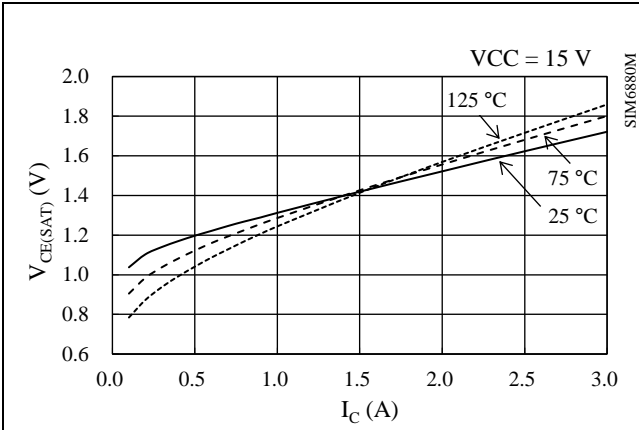


Figure 15-33.   IGBT $V_{CE(SAT)}$ vs. $I_C$
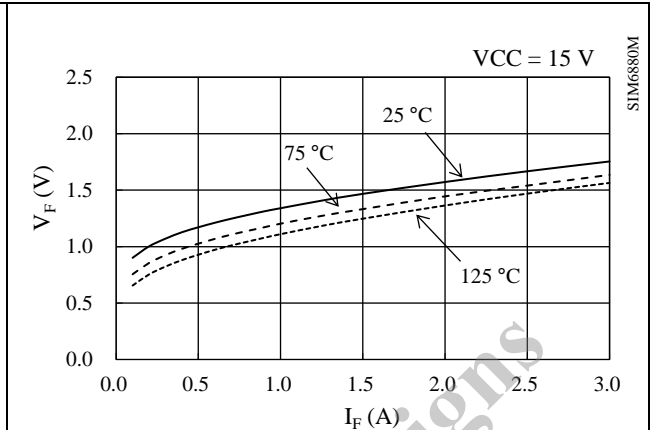


Figure 15-34.   FRD $V_F$ vs. $I_F$

### 15.3.1.4. SIM6822MV
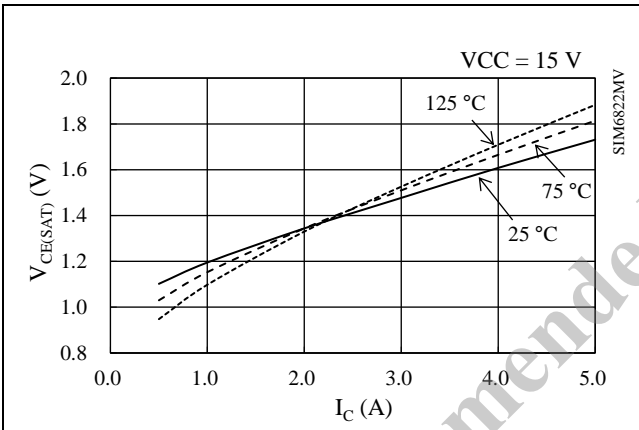


Figure 15-35.   IGBT $V_{CE(SAT)}$ vs. $I_C$
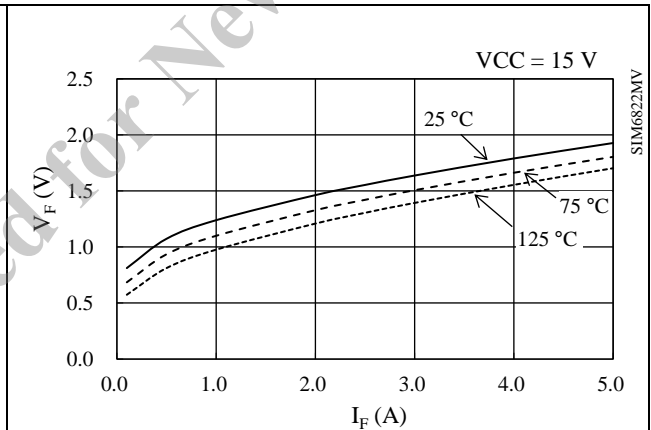


Figure 15-36.   FRD $V_F$ vs. $I_F$

## 15.3.2 Switching Loss Curves

Conditions: VBB pin voltage = 300 V, half-bridge circuit with inductive load.
Switching Loss, E, is the sum of turn-on loss and turn-off loss.

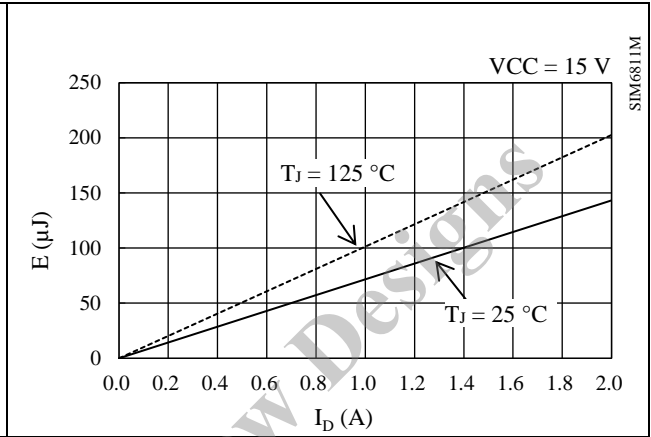### 15.3.2.1. SIM6811M
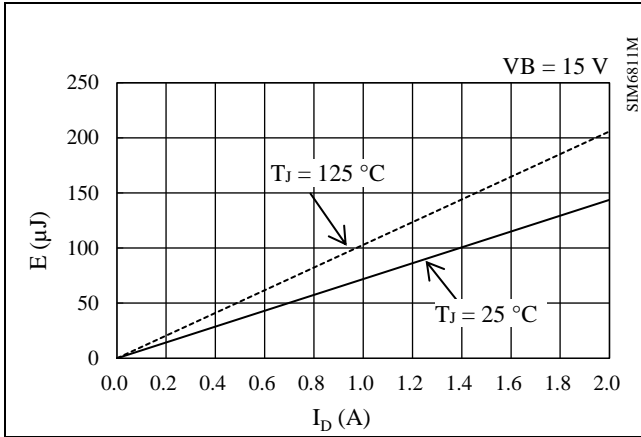


Figure 15-37.   High-side Switching Loss



Figure 15-38.   Low-side Switching Loss

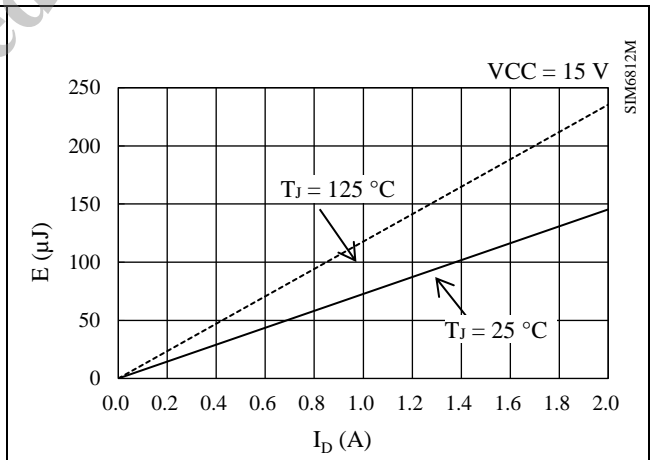### 15.3.2.2. SIM6812M
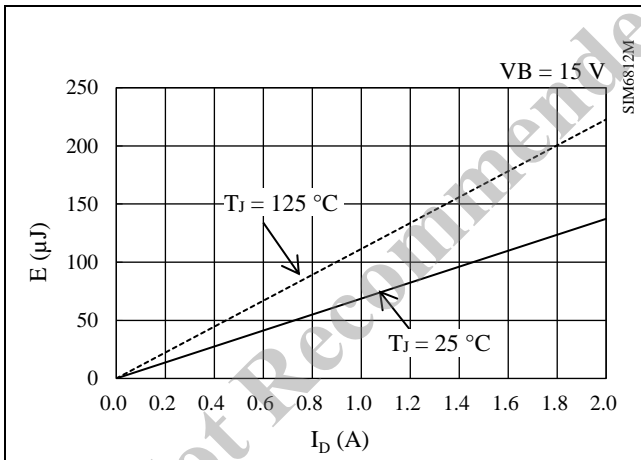


Figure 15-39.   High-side Switching Loss



Figure 15-40.   Low-side Switching Loss

### 15.3.2.3. SIM6880M
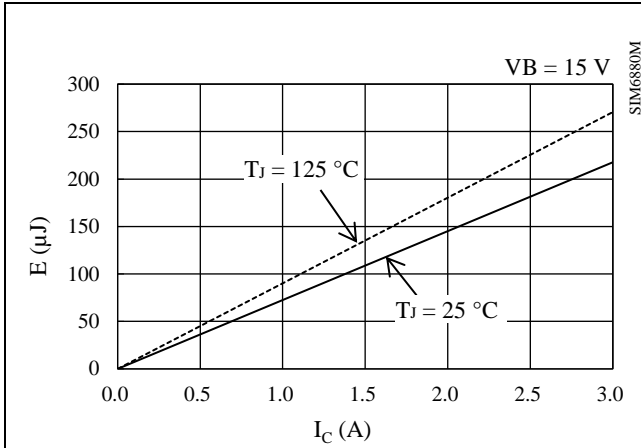


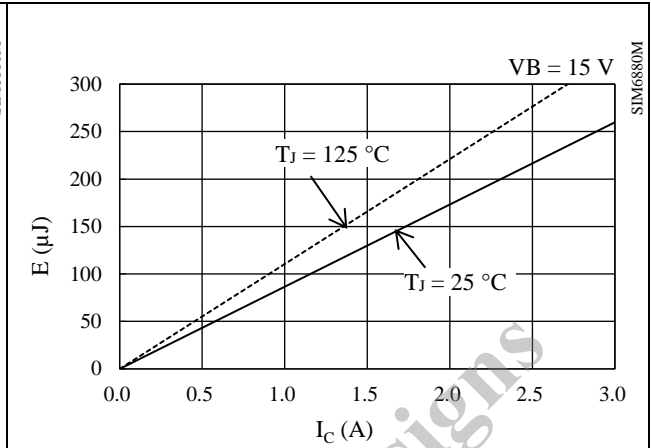Figure 15-41.    High-side Switching Loss



Figure 15-42.    Low-side Switching Loss
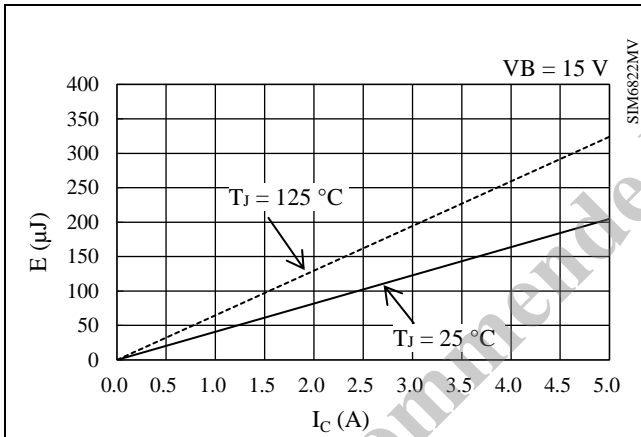
### 15.3.2.4. SIM6822MV



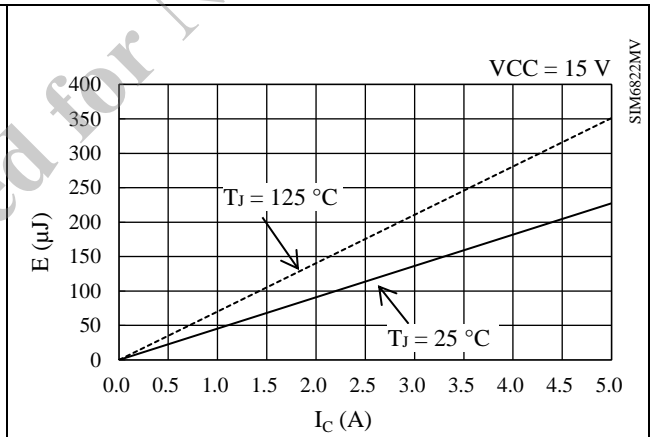Figure 15-43.    High-side Switching Loss



Figure 15-44.    Low-side Switching Loss

## 15.4 Allowable Effective Current Curves

The following curves represent allowable effective currents in 3-phase sine-wave PWM driving with parameters such as typical $R_{DS(ON)}$ or $V_{CE(SAT)}$, and typical switching losses.

Operating conditions: VBB pin input voltage, $V_{DC}$ = 300 V; VCC pin input voltage, $V_{CC}$ = 15 V; modulation index, M = 0.9; motor power factor, cosθ = 0.8; junction temperature, $T_J$ = 150 °C.

### 15.4.1 SIM6811M

Figure 15-45.    Allowable Effective Current ($f_C$ = 2 kHz): SIM6811M

Figure 15-46.    Allowable Effective Current ($f_C$ = 16 kHz): SIM6811M

### 15.4.2   SIM6812M
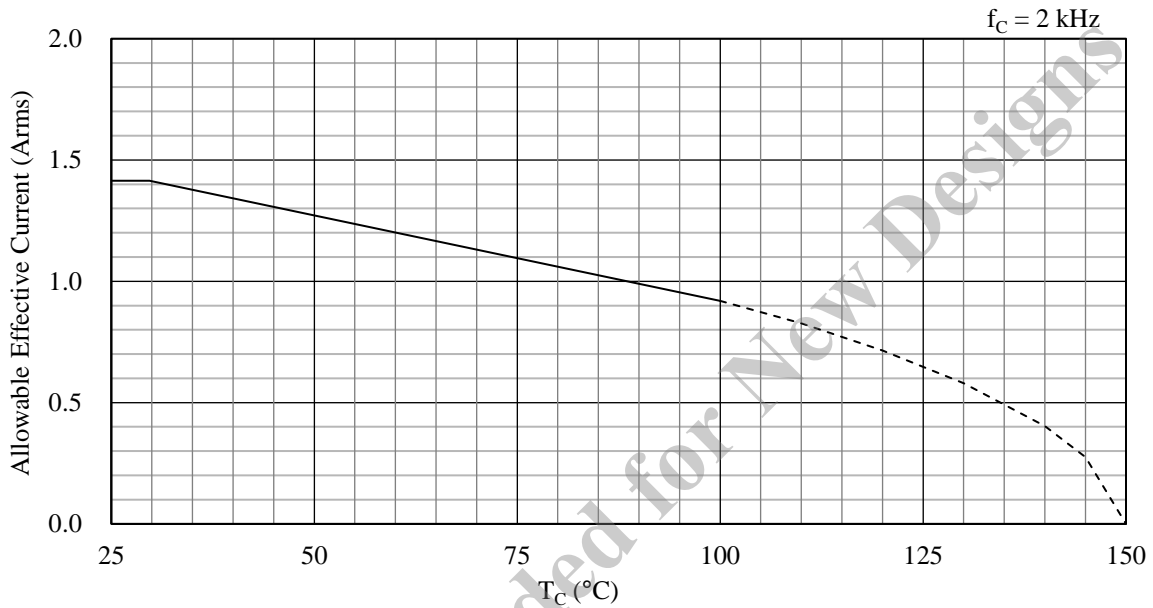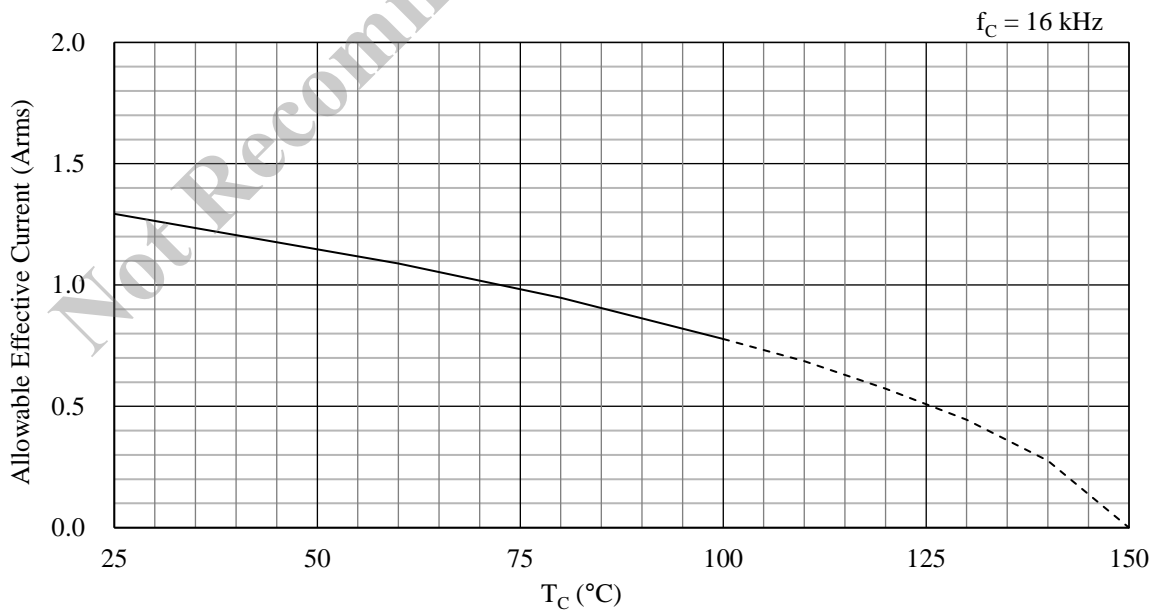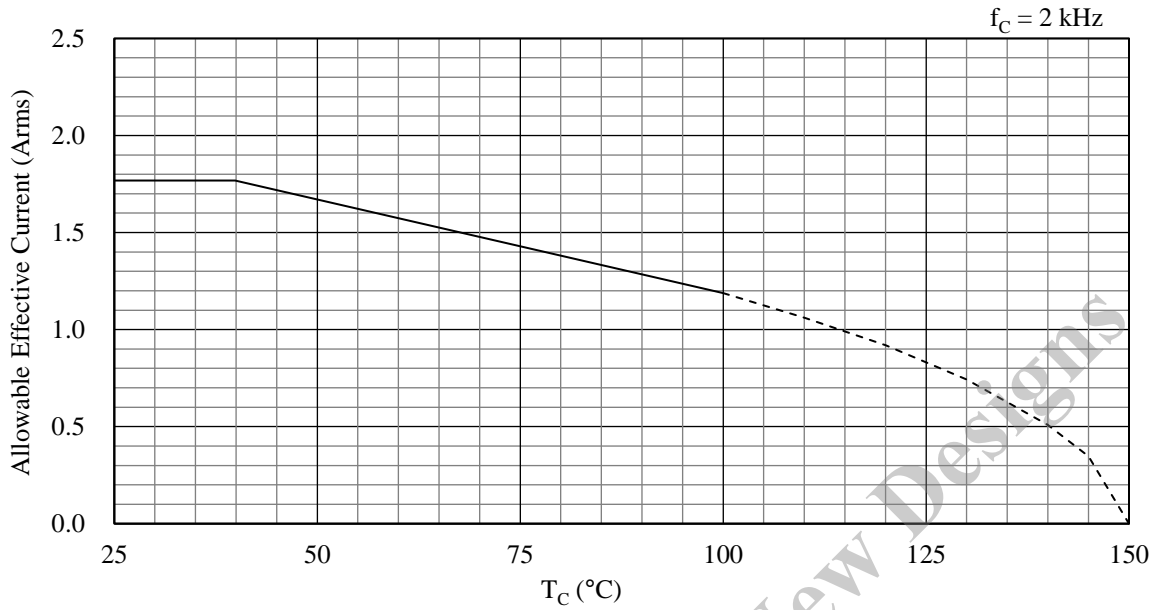


Figure 15-47.   Allowable Effective Current ($f_C = 2$ kHz): SIM6812M



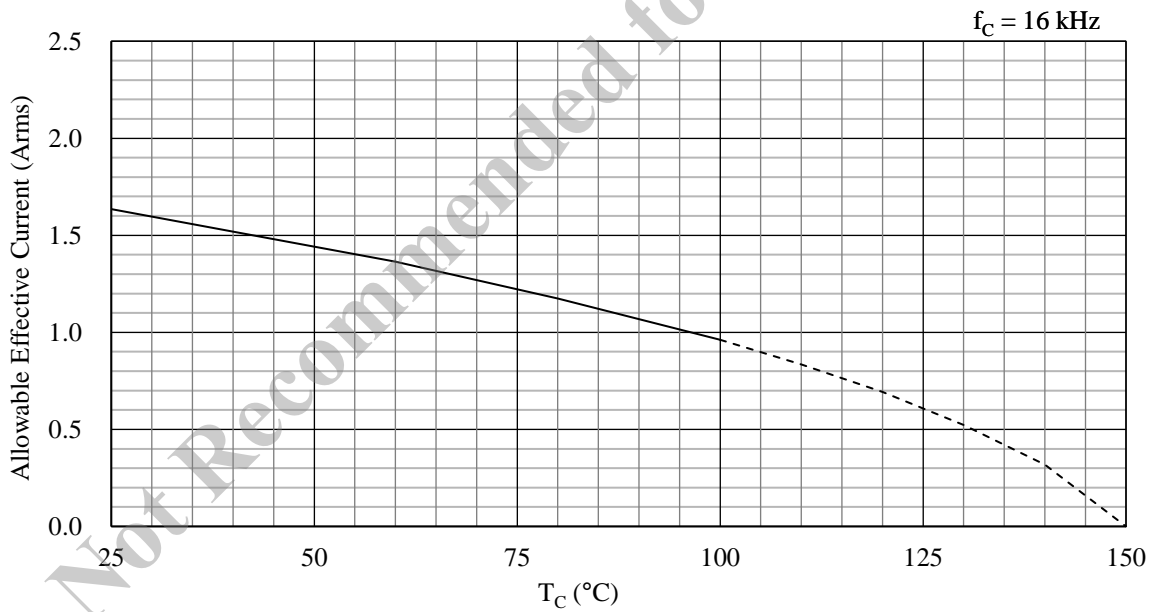Figure 15-48.   Allowable Effective Current ($f_C = 16$ kHz): SIM6812M
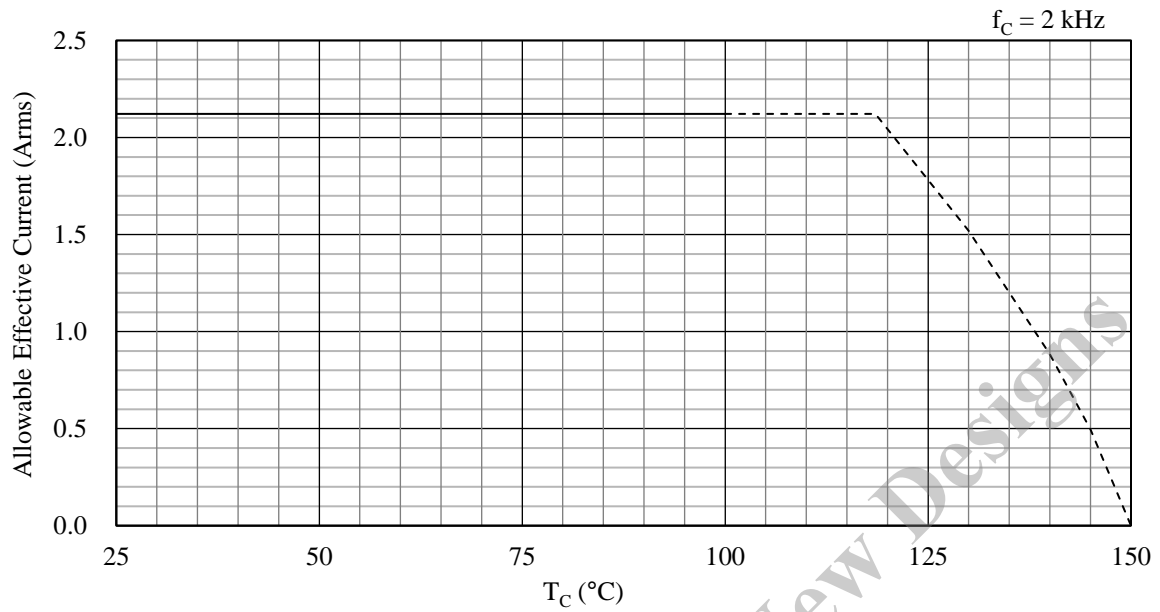
### 15.4.3 SIM6880M



Figure 15-49.    Allowable Effective Current ($f_C$ = 2 kHz): SIM6880M
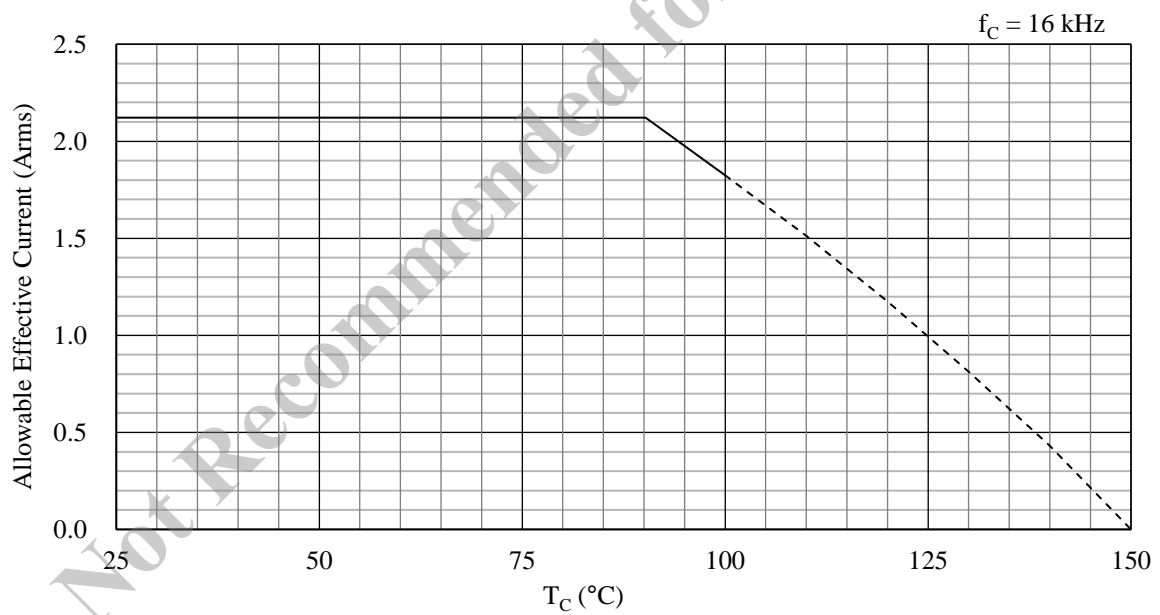


Figure 15-50.    Allowable Effective Current ($f_C$ = 16 kHz): SIM6880M

### 15.4.4   SIM6822MV
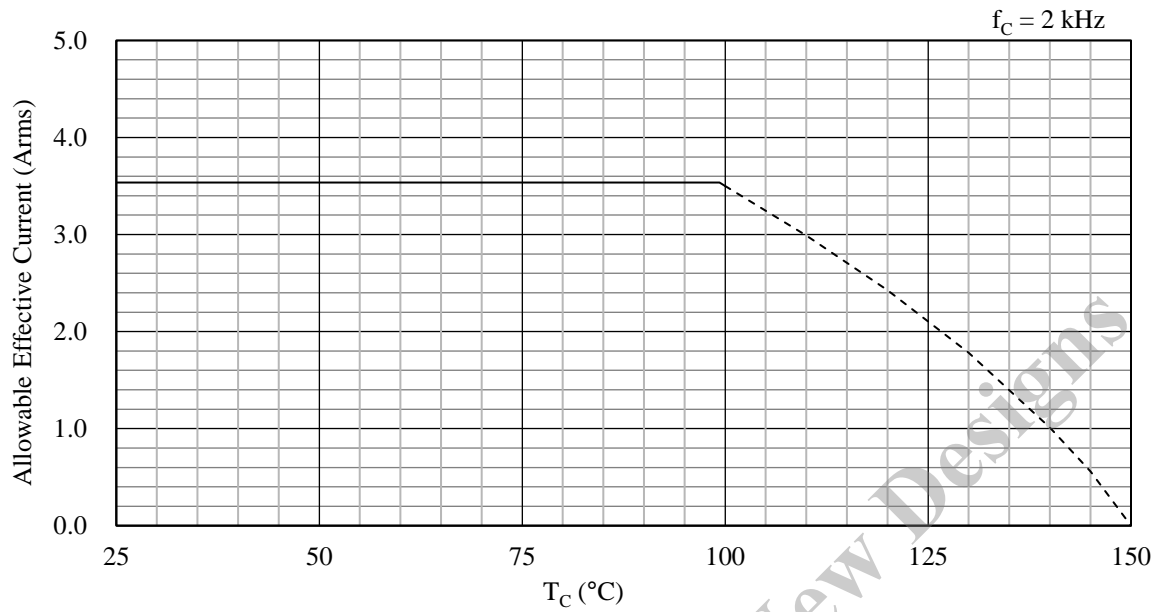


Figure 15-51.    Allowable Effective Current ($f_C$ = 2 kHz): SIM6822MV
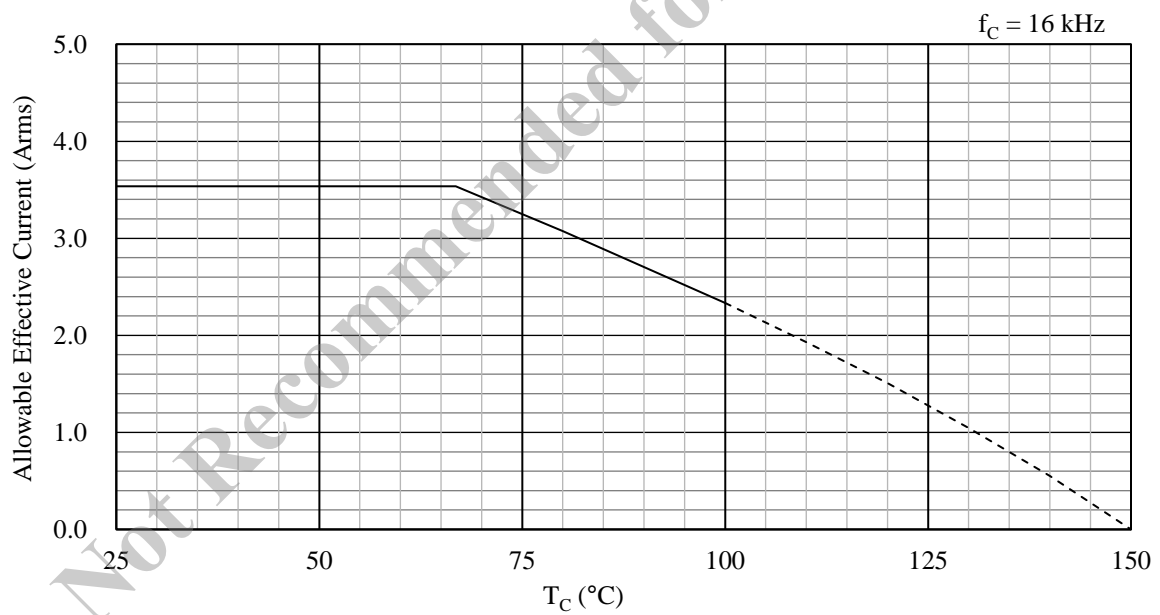


Figure 15-52.    Allowable Effective Current ($f_C$ = 16 kHz): SIM6822MV

## 15.5  Short Circuit SOAs (Safe Operating Areas)

This section provides the graphs illustrating the short circuit SOAs of the SIM6800M/MV series devices whose output transistors consist of built-in IGBTs.

Conditions: $V_{DC} \leq 400$ V, $13.5$ V $\leq$ VCC $\leq 16.5$ V, $T_J = 125$ °C, 1 pulse.

Figure 15-53.    Short Circuit SOA: SIM6880M
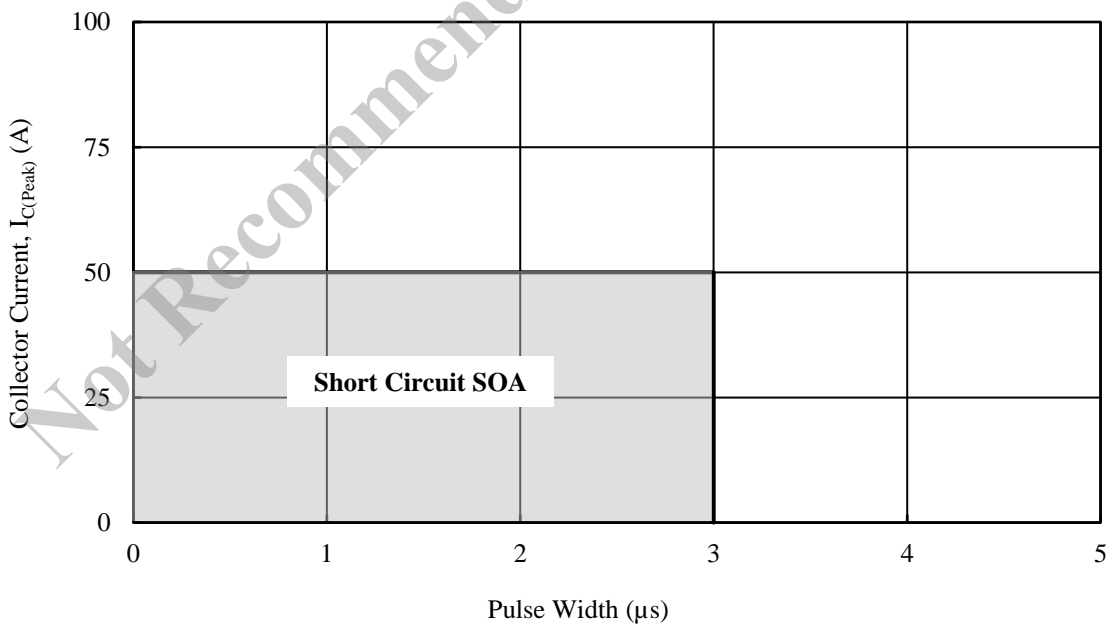
Figure 15-54.    Short Circuit SOA: SIM6822MV

## 16.  Pattern Layout Example

This section contains the schematic diagrams of a PCB pattern layout example using an SIM6800M/MV series device. For more details on through holes, see Section 10.



Figure 16-1.   Top View



Figure 16-2.   Bottom View

Figure 16-3.    Circuit Diagram of PCB Pattern Layout Example

## 17.  Typical Motor Driver Application

This section contains the information on the typical motor driver application listed in the previous section, including a circuit diagram, specifications, and the bill of the materials used.

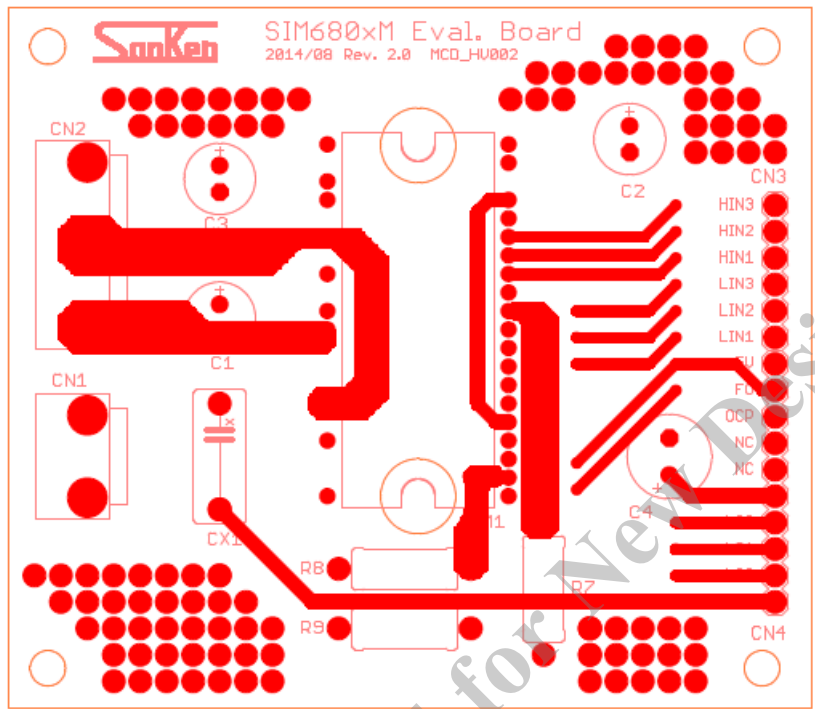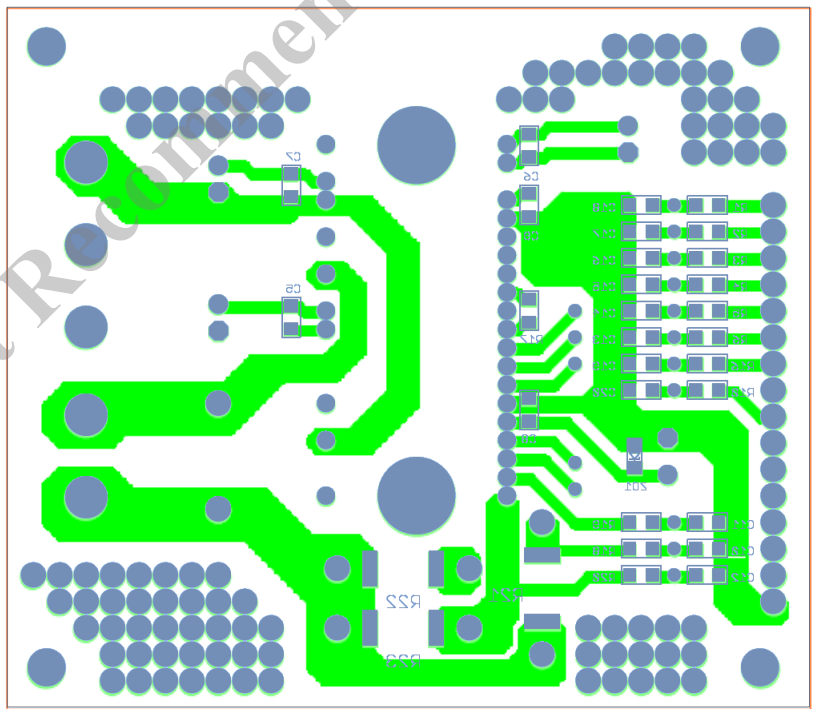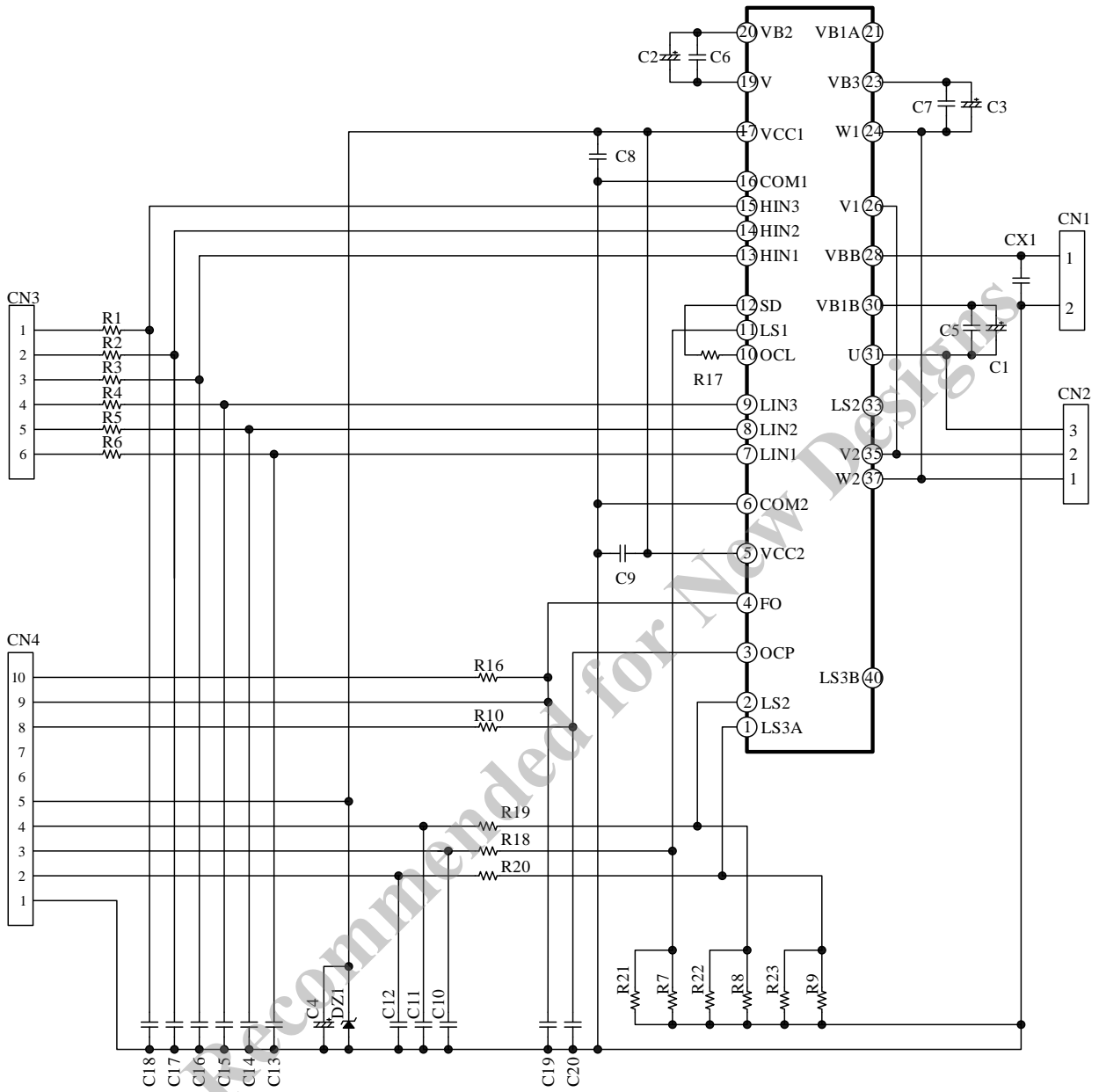● **Motor Driver Specifications**

| IC | SIM6822MV |
|---|---|
| Main Supply Voltage, $V_{DC}$ | 300 VDC (typ.) |
| Rated Output Power | 500 W |

● **Circuit Diagram**

See Figure 16-3.

● **Bill of Materials**

| Symbol | Part Type | Ratings | Symbol | Part Type | Ratings |
|---|---|---|---|---|---|
| C1 | Electrolytic | 47 µF, 50 V | R3 | General | 100 Ω, 1/8 W |
| C2 | Electrolytic | 47 µF, 50 V | R4 | General | 100 Ω, 1/8 W |
| C3 | Electrolytic | 47 µF, 50 V | R5 | General | 100 Ω, 1/8 W |
| C4 | Electrolytic | 100 µF, 50 V | R6 | General | 100 Ω, 1/8 W |
| C5 | Ceramic | 0.1 µF, 50 V | R7* | Metal plate | 0.15 Ω, 2 W |
| C6 | Ceramic | 0.1 µF, 50 V | R8* | Metal plate | 0.15 Ω, 2 W |
| C7 | Ceramic | 0.1 µF, 50 V | R9* | Metal plate | 0.15 Ω, 2 W |
| C8 | Ceramic | 0.1 µF, 50 V | R10 | General | 100 Ω, 1/8 W |
| C9 | Ceramic | 0.1 µF, 50 V | R16 | General | 3.3 kΩ, 1/8 W |
| C10 | Ceramic | 100 pF, 50 V | R17 | General | 0 kΩ, 1/8 W |
| C11 | Ceramic | 100 pF, 50 V | R18 | General | 100 Ω, 1/8 W |
| C12 | Ceramic | 100 pF, 50 V | R19 | General | 100 Ω, 1/8 W |
| C13 | Ceramic | 100 pF, 50 V | R20 | General | 100 Ω, 1/8 W |
| C14 | Ceramic | 100 pF, 50 V | R21 | General | Open |
| C15 | Ceramic | 100 pF, 50 V | R22 | General | Open |
| C16 | Ceramic | 100 pF, 50 V | R23 | General | Open |
| C17 | Ceramic | 100 pF, 50 V | ZD1 | Zener diode | $V_Z$ = 21 V (max.) |
| C18 | Ceramic | 100 pF, 50 V | IPM1 | IC | SIM6822MV |
| C19 | Ceramic | 0.01 µF, 50 V | CN1 | Pin header | Equiv. to B2P3-VH |
| C20 | Ceramic | 100 pF, 50 V | CN2 | Pin header | Equiv. to B2P5-VH |
| CX1 | Film | 0.033 µF, 630 V | CN3 | Connector | Equiv. to MA06-1 |
| R1 | General | 100 Ω, 1/8 W | CN4 | Connector | Equiv. to MA10-1 |
| R2 | General | 100 Ω, 1/8 W | | | |

\* Refers to a part that requires adjustment based on operation performance in an actual application.

# Important Notes

● All data, illustrations, graphs, tables and any other information included in this document (the "Information") as to Sanken's products listed herein (the "Sanken Products") are current as of the date this document is issued. The Information is subject to any change without notice due to improvement of the Sanken Products, etc. Please make sure to confirm with a Sanken sales representative that the contents set forth in this document reflect the latest revisions before use.

● The Sanken Products are intended for use as components of general purpose electronic equipment or apparatus (such as home appliances, office equipment, telecommunication equipment, measuring equipment, etc.). Prior to use of the Sanken Products, please put your signature, or affix your name and seal, on the specification documents of the Sanken Products and return them to Sanken. When considering use of the Sanken Products for any applications that require higher reliability (such as transportation equipment and its control systems, traffic signal control systems or equipment, disaster/crime alarm systems, various safety devices, etc.), you must contact a Sanken sales representative to discuss the suitability of such use and put your signature, or affix your name and seal, on the specification documents of the Sanken Products and return them to Sanken, prior to the use of the Sanken Products. The Sanken Products are not intended for use in any applications that require extremely high reliability such as: aerospace equipment; nuclear power control systems; and medical equipment or systems, whose failure or malfunction may result in death or serious injury to people, i.e., medical devices in Class III or a higher class as defined by relevant laws of Japan (collectively, the "Specific Applications"). Sanken assumes no liability or responsibility whatsoever for any and all damages and losses that may be suffered by you, users or any third party, resulting from the use of the Sanken Products in the Specific Applications or in manner not in compliance with the instructions set forth herein.

● In the event of using the Sanken Products by either (i) combining other products or materials or both therewith or (ii) physically, chemically or otherwise processing or treating or both the same, you must duly consider all possible risks that may result from all such uses in advance and proceed therewith at your own responsibility.

● Although Sanken is making efforts to enhance the quality and reliability of its products, it is impossible to completely avoid the occurrence of any failure or defect or both in semiconductor products at a certain rate. You must take, at your own responsibility, preventative measures including using a sufficient safety design and confirming safety of any equipment or systems in/for which the Sanken Products are used, upon due consideration of a failure occurrence rate and derating, etc., in order not to cause any human injury or death, fire accident or social harm which may result from any failure or malfunction of the Sanken Products. Please refer to the relevant specification documents and Sanken's official website in relation to derating.

● No anti-radioactive ray design has been adopted for the Sanken Products.

● The circuit constant, operation examples, circuit examples, pattern layout examples, design examples, recommended examples, all information and evaluation results based thereon, etc., described in this document are presented for the sole purpose of reference of use of the Sanken Products.

● Sanken assumes no responsibility whatsoever for any and all damages and losses that may be suffered by you, users or any third party, or any possible infringement of any and all property including intellectual property rights and any other rights of you, users or any third party, resulting from the Information.

● No information in this document can be transcribed or copied or both without Sanken's prior written consent.

● Regarding the Information, no license, express, implied or otherwise, is granted hereby under any intellectual property rights and any other rights of Sanken.

● Unless otherwise agreed in writing between Sanken and you, Sanken makes no warranty of any kind, whether express or implied, including, without limitation, any warranty (i) as to the quality or performance of the Sanken Products (such as implied warranty of merchantability, and implied warranty of fitness for a particular purpose or special environment), (ii) that any Sanken Product is delivered free of claims of third parties by way of infringement or the like, (iii) that may arise from course of performance, course of dealing or usage of trade, and (iv) as to the Information (including its accuracy, usefulness, and reliability).

● In the event of using the Sanken Products, you must use the same after carefully examining all applicable environmental laws and regulations that regulate the inclusion or use or both of any particular controlled substances, including, but not limited to, the EU RoHS Directive, so as to be in strict compliance with such applicable laws and regulations.

● You must not use the Sanken Products or the Information for the purpose of any military applications or use, including but not limited to the development of weapons of mass destruction. In the event of exporting the Sanken Products or the Information, or providing them for non-residents, you must comply with all applicable export control laws and regulations in each country including the U.S. Export Administration Regulations (EAR) and the Foreign Exchange and Foreign Trade Act of Japan, and follow the procedures required by such applicable laws and regulations.

● Sanken assumes no responsibility for any troubles, which may occur during the transportation of the Sanken Products including the falling thereof, out of Sanken's distribution network.

● Although Sanken has prepared this document with its due care to pursue the accuracy thereof, Sanken does not warrant that it is error free and Sanken assumes no liability whatsoever for any and all damages and losses which may be suffered by you resulting from any possible errors or omissions in connection with the Information.

● Please refer to our official website in relation to general instructions and directions for using the Sanken Products, and refer to the relevant specification documents in relation to particular precautions when using the Sanken Products.

● All rights and title in and to any specific trademark or tradename belong to Sanken and such original right holder(s).

DSGN-CEZ-16003